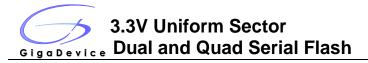
GD25Q40C

DATASHEET



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1. FEATURES

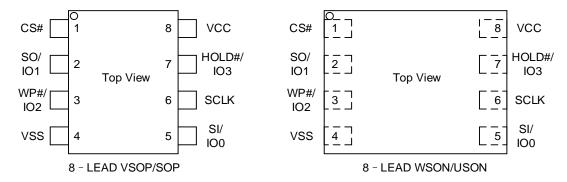
- 4M-bit Serial Flash
 - -512K-byte
 - -256 bytes per programmable page
- · Standard, Dual, Quad SPI
 - -Standard SPI: SCLK, CS#, SI, SO, WP#, HOLD#
 - -Dual SPI: SCLK, CS#, IO0, IO1, WP#, HOLD#
 - -Quad SPI: SCLK, CS#, IO0, IO1, IO2, IO3
- High Speed Clock Frequency
 - -120MHz for fast read with 30PF load
 - -Dual I/O Data transfer up to 240Mbits/s
 - -Quad I/O Data transfer up to 480Mbits/s
- ◆ Software/Hardware Write Protection
 - -Write protect all/portion of memory via software
 - -Enable/Disable protection with WP# Pin
 - -Top/Bottom block protection
- ◆ Minimum 100,000 Program/Erase Cycles
- Data Retention
 - -20-year data retention typical

- ◆ Fast Program/Erase Speed
 - -Page Program time: 0.6ms typical
 - -Sector Erase time: 45ms typical
 - -Block Erase time: 0.15/0.25s typical
 - -Chip Erase time: 2.5s typical
- ◆ Flexible Architecture
 - -Uniform Sector of 4K-byte
- -Uniform Block of 32/64K-byte
- ◆ Low Power Consumption
 - -1µA typical deep power down current
 - -1µA typical standby current
- Advanced Security Features
 - -128-Bit Unique ID for each device
 - -4x256-Byte Security Registers With OTP Locks
 - -Serial Flash Discoverable Parameters (SFDP) Register
- Single Power Supply Voltage
 - -Full voltage range: 2.7~3.6V
- Allows XIP (execute in place) Operation
 - -Continuous Read With 8/16/32/64-byte Wrap

2. GENERAL DESCRIPTION

The GD25Q40C (4M-bit) Serial flash supports the standard Serial Peripheral Interface (SPI), and supports the Dual/Quad SPI: Serial Clock, Chip Select, Serial Data I/O0 (SI), I/O1 (SO), I/O2 (WP#), and I/O3 (HOLD#). The Dual I/O data is transferred with speed of 240Mbits/s and the Quad I/O & Quad output data is transferred with speed of 480Mbits/s.

CONNECTION DIAGRAM

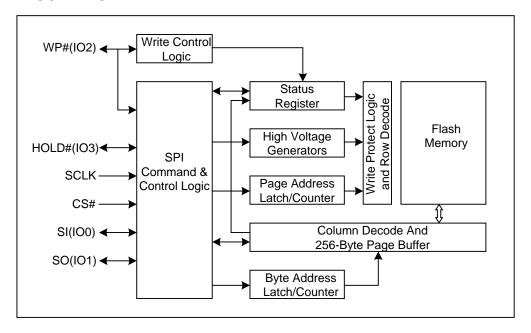


PIN DESCRIPTION

IN DECORAL FIGH						
Pin Name	I/O	Description				
CS#	I	Chip Select Input				
SO (IO1)	I/O	Data Output (Data Input Output 1)				
WP# (IO2)	I/O	Write Protect Input (Data Input Output 2)				
vss		Ground				
SI (IO0)	I/O	Data Input (Data Input Output 0)				
SCLK	I	Serial Clock Input				
HOLD# (IO3) I/O		Hold Input (Data Input Output 3)				
VCC		Power Supply				

Note: CS# must be driven high if chip is not selected. Please don't leave CS# floating any time after power is on.

BLOCK DIAGRAM





3. MEMORY ORGANIZATION

GD25Q40C

Each device has	Each block has	Each sector has	Each page has	
512K	64/32K	4K	256	bytes
2K	256/128	16	-	pages
128	16/8	-	-	sectors
8/16	-	-	-	blocks

UNIFORM BLOCK SECTOR ARCHITECTURE GD25Q40C 64K Bytes Block Sector Architecture

Block	Sector	Address range		
	127	07F000H	07FFFFH	
7				
	112	070000H	070FFFH	
	111	06F000H	06FFFFH	
6				
	96	060000H	060FFFH	
	47	02F000H	02FFFFH	
2				
	32	020000H	020FFFH	
	31	01F000H	01FFFFH	
1				
	16	010000H	010FFFH	
	15	00F000H	00FFFFH	
0				
	0	000000H	000FFFH	

4. DEVICE OPERATION

SPI Mode

Standard SPI

The GD25Q40C features a serial peripheral interface on 4 signals bus: Serial Clock (SCLK), Chip Select (CS#), Serial Data Input (SI) and Serial Data Output (SO). Both SPI bus mode 0 and 3 are supported. Input data is latched on the rising edge of SCLK and data shifts out on the falling edge of SCLK.

Dual SPI

The GD25Q40C supports Dual SPI operation when using the "Dual Output Fast Read" and "Dual I/O Fast Read" (3BH and BBH) commands. These commands allow data to be transferred to or from the device at two times the rate of the standard SPI. When using the Dual SPI command the SI and SO pins become bidirectional I/O pins: IOO and IO1.

Quad SPI

The GD25Q40C supports Quad SPI operation when using the "Quad Output Fast Read" (6BH), "Quad I/O Fast Read" (E7H) and "Quad Page Program" (32H) commands. These commands allow data to be transferred to or from the device at four times the rate of the standard SPI. When using the Quad SPI command the SI and SO pins become bidirectional I/O pins: IO0 and IO1, and WP# and HOLD# pins become IO2 and IO3. Quad SPI commands require the non-volatile Quad Enable bit (QE) in Status Register to be set.

Hold

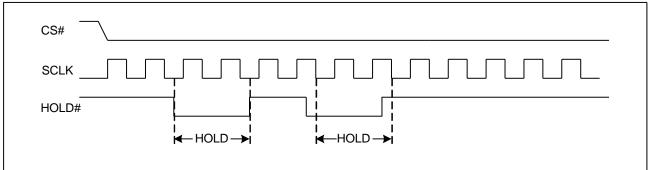
The HOLD# function is only available when QE=0, If QE=1, The HOLD# functions is disabled, the pin acts as dedicated data I/O pin.

The HOLD# signal goes low to stop any serial communications with the device, but doesn't stop the operation of write status register, programming, or erasing in progress.

The operation of HOLD, need CS# keep low, and starts on falling edge of the HOLD# signal, with SCLK signal being low (if SCLK is not being low, HOLD operation will not start until SCLK being low). The HOLD condition ends on rising edge of HOLD# signal with SCLK being low (If SCLK is not being low, HOLD operation will not end until SCLK being low).

The SO is high impedance, both SI and SCLK don't care during the HOLD operation, if CS# drives high during HOLD operation, it will reset the internal logic of the device. To re-start communication with chip, the HOLD# must be at high and then CS# must be at low.

Figure 1. Hold Condition



5. DATA PROTECTION

The GD25Q40C provide the following data protection methods:

- Write Enable (WREN) command: The WREN command is set the Write Enable Latch bit (WEL). The WEL bit will return to reset by the following situation:
 - -Power-Up
 - -Write Disable (WRDI)
 - -Write Status Register (WRSR)
 - -Page Program (PP)
 - -Sector Erase (SE) / Block Erase (BE) / Chip Erase (CE)
- Software Protection Mode: The Block Protect (BP4, BP3, BP2, BP1, and BP0) bits define the section of the memory array that can be read but not change.
- Hardware Protection Mode: WP# going low to protected the BP0~BP4 bits and SRP0~1 bits.
- Deep Power-Down Mode: In Deep Power-Down Mode, all commands are ignored except the Release from Deep Power-Down Mode command.

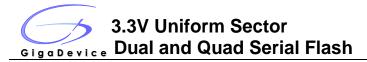
;	Status R	Register	Conten	t	Memory Content					
BP4	BP3	BP2	BP1	BP0	Blocks	Addresses	Density	Portion		
Χ	Х	0	0	0	NONE	NONE	NONE	NONE		
0	0	0	0	1	7	070000H-07FFFFH	64KB	Upper 1/8		
0	0	0	1	0	6 and 7	060000H-07FFFFH	128KB	Upper 1/4		
0	0	0	1	1	4 to 7	040000H-07FFFFH	256KB	Upper 1/2		
0	1	0	0	1	0	000000H-00FFFFH	64KB	Lower 1/8		
0	1	0	1	0	0 and 1	000000H-01FFFFH	128KB	Lower 1/4		
0	1	0	1	1	0 to 3	000000H-03FFFFH	256KB	Lower 1/2		
0	Х	1	Х	Х	0 to 7	0 to 7 000000H-07FFFH		ALL		
1	0	0	0	1	7	7 07F000H-07FFFFH		Upper 1/128		
1	0	0	1	0	7	07E000H-07FFFFH	8KB	Upper 1/64		
1	0	0	1	1	7	07C000H-07FFFFH	16KB	Upper 1/32		
1	0	1	0	Х	7	078000H-07FFFFH	32KB	Upper 1/16		
1	0	1	1	0	7	078000H-07FFFFH	32KB	Upper 1/16		
1	1	0	0	1	0	000000H-000FFFH	4KB	Lower 1/128		
1	1	0	1	0	0	000000H-001FFFH	8KB	Lower 1/64		
1	1	0	1	1	0	000000H-003FFFH	16KB	Lower 1/32		
1	1	1	0	Х	0	000000H-007FFFH	32KB	Lower 1/16		
1	1	1	1	0	0	000000H-007FFFH	32KB	Lower 1/16		
1	Х	1	1	1	0 to 7	000000H-07FFFFH	512KB	ALL		

3.3V Uniform Sector GigaDevice Dual and Quad Serial Flash

GD25Q40C

Table1.1 GD25Q40C Protected area size (CMP=1)

:	Status F	Register	Conten	t		Memory Content					
BP4	BP3	P3 BP2 BP1 BP0		BP0	Blocks	Blocks Addresses		Portion			
Х	Х	0	0	0	0 to 7	000000H-07FFFFH	512KB	ALL			
0	0	0	0	1	0 to 6	000000H-06FFFFH	448KB	Lower 7/8			
0	0	0	1	0	0 to 5	000000H-05FFFFH	384KB	Lower 3/4			
0	0	0	1	1	0 to 3	000000H-03FFFFH	256KB	Lower 1/2			
0	1	0	0	1	1 to 7	010000H-07FFFFH	448KB	Upper 7/8			
0	1	0	1	0	2 to 7	020000H-07FFFFH	384KB	Upper 3/4			
0	1	0	1	1	4 to 7	040000H-07FFFFH	256KB	Upper 1/2			
0	Х	1	Х	Х	NONE	NONE	NONE	NONE			
1	0	0	0	1	0 to 7	000000H-07EFFFH	508KB	Lower 127/128			
1	0	0	1	0	0 to 7	000000H-07DFFFH	504KB	Lower 63/64			
1	0	0	1	1	0 to 7	000000H-07BFFFH	496KB	Lower 31/32			
1	0	1	0	Х	0 to 7	000000H-077FFFH	480KB	Lower 15/16			
1	0	1	1	0	0 to 7	000000H-077FFFH	480KB	Lower 15/16			
1	1	0	0	1	0 to 7	001000H-07FFFFH	508KB	Upper 127/128			
1	1	0	1	0	0 to 7	002000H-07FFFFH	504KB	Upper 63/64			
1	1	0	1	1	0 to 7	004000H-07FFFFH	496KB	Upper 31/32			
1	1	1	0	Х	0 to 7	008000H-07FFFFH	480KB	Upper 15/16			
1	1	1	1	0	0 to 7	008000H-07FFFFH	480KB	Upper 15/16			
1	Х	1	1	1	NONE	NONE	NONE	NONE			



6. STATUS REGISTER

S15	S14	S13	S12	S11	S10	S9	S8
sus	S CMP HPF		Reserved	Reserved	LB	QE	SRP1
S 7	S6	S 5	S4	S3	S2	S1	S0

The status and control bits of the Status Register are as follows:

WIP bit.

The Write in Progress (WIP) bit indicates whether the memory is busy in program/erase/write status register progress. When WIP bit sets to 1, means the device is busy in program/erase/write status register progress, when WIP bit sets 0, means the device is not in program/erase/write status register progress.

WEL bit.

The Write Enable Latch (WEL) bit indicates the status of the internal Write Enable Latch. When set to 1 the internal Write Enable Latch is set, when set to 0 the internal Write Enable Latch is reset and no Write Status Register, Program or Erase command is accepted.

BP4, BP3, BP2, BP1, BP0 bits.

The Block Protect (BP4, BP3, BP2, BP1, and BP0) bits are non-volatile. They define the size of the area to be software protected against Program and Erase commands. These bits are written with the Write Status Register (WRSR) command. When the Block Protect (BP4, BP3, BP2, BP1, BP0) bits are set to 1, the relevant memory area (as defined in Table1).becomes protected against Page Program (PP), Sector Erase (SE) and Block Erase (BE) commands. The Block Protect (BP4, BP3, BP2, BP1, and BP0) bits can be written provided that the Hardware Protected mode has not been set. The Chip Erase (CE) command is executed, only if the Block Protect (BP2, BP1, and BP0) bits are 0 and CMP=0.

SRP1, SRP0 bits.

The Status Register Protect (SRP1 and SRP0) bits are non-volatile Read/Write bits in the status register. The SRP bits control the method of write protection: software protection, hardware protection, power supply lock-down or one time programmable protection.

SRP1	SRP0	#WP	Status Register	Description
0	0 0 X Software Pro		Software Protected	The Status Register can be written to after a Write Enable
		^	Software Protected	command, WEL=1.(Default)
0	1	0	Hardware Protected	WP#=0, the Status Register locked and cannot be written
U	I	O	Haidware Protected	to.
0	4	1	Hardware Unprotected	WP#=1, the Status Register is unlocked and can be written
U	I	1	Hardware Oriprotected	to after a Write Enable command, WEL=1.
1	0	X	Power Supply Lock-Down ^{(1) (2)}	Status Register is protected and cannot be written to again
'	0	^	Power Supply Lock-Down (**)	until the next Power-Down, Power-Up cycle.
1	1 X One Time Program ⁽²⁾		One Time Program ⁽²⁾	Status Register is permanently protected and cannot be
	1	^	One time Plogram	written to.

NOTE:

- 1. When SRP1, SRP0= (1, 0), a Power-Down, Power-Up cycle will change SRP1, SRP0 to (0, 0) state.
- 2. This feature is available on special order. Please contact GigaDevice for details.

QE bit.

The Quad Enable (QE) bit is a non-volatile Read/Write bit in the Status Register that allows Quad operation. When the QE bit is set to 0 (Default) the WP# pin and HOLD# pin are enable. When the QE pin is set to 1, the Quad IO2 and IO3

GD25Q40C

pins are enabled. (It is best to set the QE bit to 0 to avoid short issues if the WP# or HOLD# pin is tied directly to the power supply or ground.)

LB bit.

The LB bit is a non-volatile One Time Program (OTP) bit in Status Register (S10) that provide the write protect control and status to the Security Registers. The default state of LB is 0, the security registers are unlocked. LB can be set to 1 individually using the Write Register instruction. LB is One Time Programmable, once it's set to 1, the Security Registers will become read-only permanently.

CMP bit

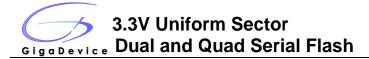
The CMP bit is a non-volatile Read/Write bit in the Status Register (S14). It is used in conjunction the BP4-BP0 bits to provide more flexibility for the array protection. Please see the Status registers Memory Protection table for details. The default setting is CMP=0.

HPF bit

The High Performance Flag (HPF) bit indicates the status of High Performance Mode (HPM). When HPF bit sets to 1, it means the device is in High Performance Mode, when HPF bit sets 0 (default), it means the device is not in High Performance Mode.

SUS bit

The SUS bit is a read only bit in the status register (S15) that is set to 1 after executing an Erase/Program Suspend (75H) command. The SUS bit is cleared to 0 by Erase/Program Resume (7AH) command as well as a power-down, power-up cycle.



7. COMMANDS DESCRIPTION

All commands, addresses and data are shifted in and out of the device, beginning with the most significant bit on the first rising edge of SCLK after CS# is driven low. Then, the one-byte command code must be shifted in to the device, most significant bit first on SI, each bit being latched on the rising edges of SCLK.

See Table2, every command sequence starts with a one-byte command code. Depending on the command, this might be followed by address bytes, or by data bytes, or by both or none. CS# must be driven high after the last bit of the command sequence has been shifted in. For the commands of Read, Fast Read, Read Status Register or Release from Deep Power-Down, and Read Device ID, the shifted-in command sequence is followed by a data-out sequence. All read instruction can be completed after any bit of the data-out sequence is being shifted out, and then CS# must be driven high to return to deselected status.

For the commands of Page Program, Sector Erase, Block Erase, Chip Erase, Write Status Register, Write Enable, Write Disable or Deep Power-Down command, CS# must be driven high exactly at a byte boundary, otherwise the command is rejected, and is not executed. That means CS# must be driven high when the number of clock pulses after CS# being driven low is an exact multiple of eight. For Page Program, if CS# is driven high at any time the input byte is not a full byte, nothing will happen and WEL will not be reset.

Table2. Commands (Standard/Dual/Quad SPI)

Command Name	Byte 1	Byte 2	Byte 3	Byte 4	Byte 5	Byte 6	n-Bytes
Write Enable	06H						
Write Disable	04H						
Volatile SR	50H						
Write Enable							
Read Status Register	05H	(S7-S0)					(continuous)
Read Status Register-1	35H	(S15-S8)					(continuous)
Write Status Register	01H	S7-S0	S15-S8				
Read Data	03H	A23-A16	A15-A8	A7-A0	(D7-D0)	(Next byte)	(continuous)
Fast Read	0BH	A23-A16	A15-A8	A7-A0	dummy	(D7-D0)	(continuous)
Dual Output	3BH	A23-A16	A15-A8	A7-A0	dummy	(D7-D0) ⁽¹⁾	(continuous)
Fast Read							
Dual I/O	BBH	A23-A8 ⁽²⁾	A7-A0	(D7-D0) ⁽¹⁾			(continuous)
Fast Read			M7-M0 ⁽²⁾				
Quad Output	6BH	A23-A16	A15-A8	A7-A0	dummy	(D7-D0) ⁽³⁾	(continuous)
Fast Read							
Quad I/O	EBH	A23-A0	dummy ⁽⁵⁾	(D7-D0) ⁽³⁾			(continuous)
Fast Read		M7-M0 ⁽⁴⁾					
Quad I/O Word	E7H	A23-A0	dummy ⁽⁶⁾	(D7-D0) ⁽³⁾			(continuous)
Fast Read ⁽⁷⁾		M7-M0 ⁽⁴⁾					
Continuous Read Mode	FFH						
Reset							
Page Program	02 H	A23-A16	A15-A8	A7-A0	D7-D0	Next byte	
Quad Page Program	32H	A23-A16	A15-A8	A7-A0	D7-D0		
Sector Erase	20H	A23-A16	A15-A8	A7-A0			
Block Erase(32K)	52H	A23-A16	A15-A8	A7-A0			
Block Erase(64K)	D8H	A23-A16	A15-A8	A7-A0			
Chip Erase	C7/60						
	Н						
Enable Reset	66H						
Reset	99H						
Set Burst with Wrap	77H	W6-W4					
Program/Erase	75H						

3.3V Uniform Sector Gigabevice Dual and Quad Serial Flash

GD25Q40C

Suspend							
Program/Erase Resume	7AH						
Deep Power-Down	В9Н						
Release From Deep	ABH	dummy	dummy	dummy	(DID7-		(continuous)
Power-Down, And					DID0)		
Read Device ID							
Release From Deep	ABH						
Power-Down							
Manufacturer/	90H	00H	00H	00H	(MID7-	(DID7-	(continuous)
Device ID					MID0)	DID0)	
High Performance	АЗН	dummy	dummy	dummy			
Mode							
Read Serial Flash	5AH	A23-A16	A15-A8	A7-A0	dummy	(D7-D0)	(continuous)
Discoverable							
Parameter							
Read Identification	9FH	(MID7-	(JDID15-	(JDID7-			(continuous)
		M0)	JDID8)	JDID0)			
Read Unique ID	4BH	00H	00H	00H	dummy	(UID7-	(continuous)
						UID0)	
Erase Security	44H	A23-A16	A15-A8	A7-A0			
Registers(8)							
Program Security	42H	A23-A16	A15-A8	A7-A0	D7-D0	D7-D0	
Registers(8)							
Read Security	48H	A23-A16	A15-A8	A7-A0	dummy	(D7-D0)	
Registers(8)							

NOTE:

1. Dual Output data

IO0 = (D6, D4, D2, D0)

IO1 = (D7, D5, D3, D1)

2. Dual Input Address

IO0 = A22, A20, A18, A16, A14, A12, A10, A8

A6, A4, A2, A0, M6, M4, M2, M0

IO1 = A23, A21, A19, A17, A15, A13, A11, A9

A7, A5, A3, A1, M7, M5, M3, M1

3. Quad Output Data

IO0 = (D4, D0,)

IO1 = (D5, D1,)

IO2 = (D6, D2,)

IO3 = (D7, D3,....)

4. Quad Input Address

IO0 = A20, A16, A12, A8, A4, A0, M4, M0

IO1 = A21, A17, A13, A9, A5, A1, M5, M1

IO2 = A22, A18, A14, A10, A6, A2, M6, M2

IO3 = A23, A19, A15, A11, A7, A3, M7, M3

5. Fast Read Quad I/O Data

IO0 = (x, x, x, x, D4, D0,...)

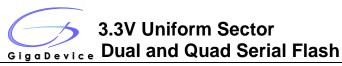
IO1 = (x, x, x, x, D5, D1,...)

IO2 = (x, x, x, x, D6, D2,...)

IO3 = (x, x, x, x, D7, D3,...)

6. Fast Word Read Quad I/O Data

IO0 = (x, x, D4, D0,...)



IO1 = (x, x, D5, D1,...)

IO2 = (x, x, D6, D2,...)

IO3 = (x, x, D7, D3,...)

- 7. Fast Word Read Quad I/O Data: the lowest address bit must be 0.
- 8. Security Registers Address:

Security Register0: A23-A16=00H, A15-A8=00H, A7-A0= Byte Address;

Security Register1: A23-A16=00H, A15-A8=01H, A7-A0= Byte Address;

Security Register2: A23-A16=00H, A15-A8=02H, A7-A0= Byte Address;

Security Register3: A23-A16=00H, A15-A8=03H, A7-A0= Byte Address.

9. Dummy bits and Wrap Bits

IO0 = (x, x, x, x, x, x, W4, x)

IO1 = (x, x, x, x, x, x, W5, x)

102 = (x, x, x, x, x, x, W6, x)

103 = (x, x, x, x, x, x, x, x)

10. Address, Continuous Read Mode bits, Dummy bits, Manufacture ID and Device ID

IOO = (A20, A16, A12, A8, A4, A0, M4, M0, x, x, x, x, MID4, MID0, DID4, DID0, ...)

IO1 = (A21, A17, A13, A9, A5, A1, M5, M1, x, x, x, x, MID5, MID1, DID5, DID1, ...)

IO2 = (A22, A18, A14, A10, A6, A2, M6, M2, x, x, x, x, MID6, MID2, DID6, DID2, ...)

IO3 = (A23, A19, A15, A11, A7, A3, M7, M3, x, x, x, x, MID7, MID3, DID7, DID3, ...)

Table of ID Definitions:

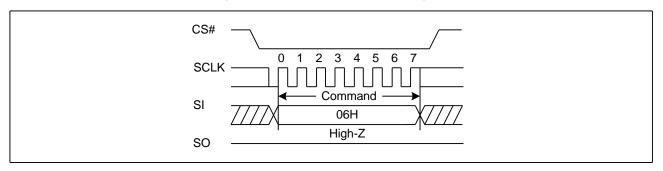
GD25Q40C

Operation Code	MID7-MID0	ID15-ID8	ID7-ID0
9FH	C8	40	13
90H	C8		12
ABH			12

7.1. Write Enable (WREN) (06H)

The Write Enable (WREN) command is for setting the Write Enable Latch (WEL) bit. The Write Enable Latch (WEL) bit must be set prior to every Page Program (PP), Sector Erase (SE), Block Erase (BE), and Chip Erase (CE), Write Status Register (WRSR) and Erase/Program Security Registers command. The Write Enable (WREN) command sequence: CS# goes low → sending the Write Enable command → CS# goes high.

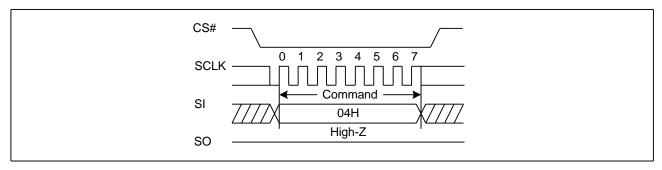
Figure 2. Write Enable Sequence Diagram



7.2. Write Disable (WRDI) (04H)

The Write Disable command is for resetting the Write Enable Latch (WEL) bit. The Write Disable command sequence: CS# goes low →Sending the Write Disable command →CS# goes high. The WEL bit is reset by following condition: Power-up and upon completion of the Write Status Register, Page Program, Sector Erase, Block Erase, Chip Erase, Erase/Program Security Registers and Reset commands.

Figure 3. Write Disable Sequence Diagram



7.3. Read Status Register (RDSR) (05H or 35H)

The Read Status Register (RDSR) command is for reading the Status Register. The Status Register may be read at any time, even while a Program, Erase or Write Status Register cycle is in progress. When one of these cycles is in progress, it is recommended to check the Write In Progress (WIP) bit before sending a new command to the device. It is also possible to read the Status Register continuously. For command code "05H", the SO will output Status Register bits S7~S0. The command code "35H", the SO will output Status Register bits S15~S8.

CS#

SCLK

0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15

SI

Command

O5H or 35H

S7-S0 or S15-S8 out

T/6 5 4 3 2 1 0 7 6 5 4 3 2 1 0 7

MSB

MSB

Figure 4. Read Status Register Sequence Diagram

7.4. Write Status Register (WRSR) (01H)

The Write Status Register (WRSR) command allows new values to be written to the Status Register. Before it can be accepted, a Write Enable (WREN) command must previously have been executed. After the Write Enable (WREN) command has been decoded and executed, the device sets the Write Enable Latch (WEL).

The Write Status Register (WRSR) command has no effect on S15, S13, S12, S11, S1 and S0 of the Status Register. CS# must be driven high after the eighth or sixteen bit of the data byte has been latched in. If not, the Write Status Register (WRSR) command is not executed. If CS# is driven high after eighth bit of the data byte, the CMP and QE bit will be cleared to 0. As soon as CS# is driven high, the self-timed Write Status Register cycle (whose duration is tw) is initiated. While the Write Status Register cycle is in progress, the Status Register may still be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Write Status Register cycle, and is 0 when it is completed. When the cycle is completed, the Write Enable Latch (WEL) is reset.

The Write Status Register (WRSR) command allows the user to change the values of the Block Protect (BP4, BP3, BP2, BP1, BP0) bits, to define the size of the area that is to be treated as read-only, as defined in Table1. The Write Status Register (WRSR) command also allows the user to set or reset the Status Register Protect (SRP) bit in accordance with the Write Protect (WP#) signal. The Status Register Protect (SRP) bit and Write Protect (WP#) signal allow the device to be put in the Hardware Protected Mode. The Write Status Register (WRSR) command is not executed once the Hardware Protected Mode is entered.

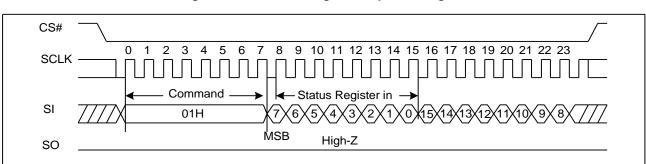


Figure 5. Write Status Register Sequence Diagram

7.5. Write Enable for Volatile Status Register (50H)

The non-volatile Status Register bits can also be written to as volatile bits. This gives more flexibility to change the system configuration and memory protection schemes quickly without waiting for the typical non-volatile bit write cycles or affecting the endurance of the Status Register non-volatile bits. The Write Enable for Volatile Status Register command must be issued prior to a Write Status Register command, and any other commands cannot be inserted between them. Otherwise, Write Enable for Volatile Status Register will be cleared. The Write Enable for Volatile Status Register command will not set the Write Enable Latch bit, it is only valid for the Write Status Register command to change the volatile Status Register bit values.

CS#

SCLK

0 1 2 3 4 5 6 7

Command(50H) →

SI

SO

High-Z

Figure 6. Write Enable for Volatile Status Register Sequence Diagram

7.6. Read Data Bytes (READ) (03H)

The Read Data Bytes (READ) command is followed by a 3-byte address (A23-A0), each bit being latched-in during the rising edge of SCLK. Then the memory content, at that address, is shifted out on SO, each bit being shifted out, at a Max frequency f_R, during the falling edge of SCLK. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out. The whole memory can, therefore, be read with a single Read Data Bytes (READ) command. Any Read Data Bytes (READ) command, while an Erase, Program or Write cycle is in progress, is rejected without having any effects on the cycle that is in progress.

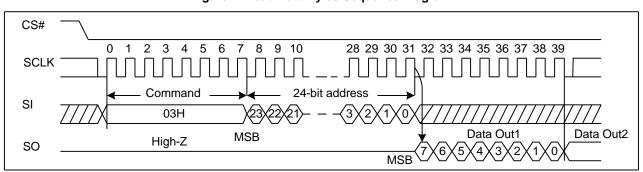


Figure 7. Read Data Bytes Sequence Diagram

Read Data Bytes at Higher Speed (Fast Read) (0BH)

The Read Data Bytes at Higher Speed (Fast Read) command is for quickly reading data out. It is followed by a 3-byte address (A23-A0) and a dummy byte, each bit being latched-in during the rising edge of SCLK. Then the memory content, at that address, is shifted out on SO, each bit being shifted out, at a Max frequency fc, during the falling edge of SCLK. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out.

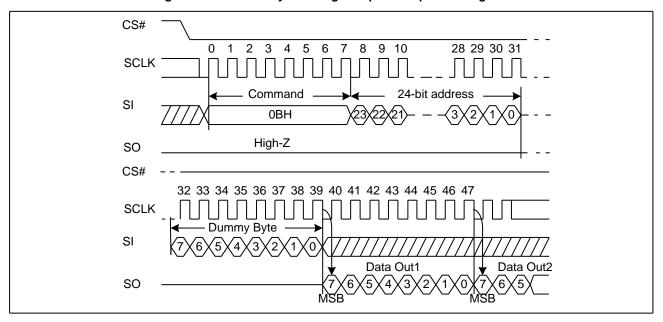
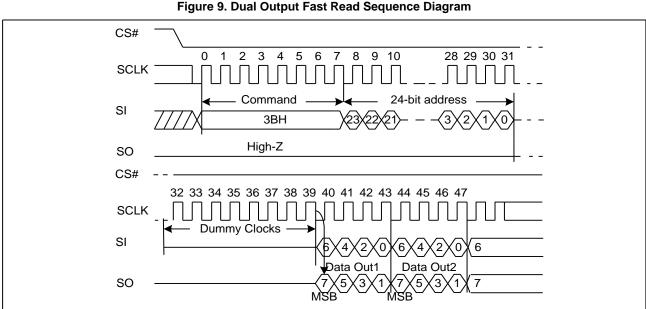


Figure 8. Read Data Bytes at Higher Speed Sequence Diagram

7.8. Dual Output Fast Read (3BH)

The Dual Output Fast Read command is followed by 3-byte address (A23-A0) and a dummy byte, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 2-bit per clock cycle from SI and SO. The command sequence is shown in followed Figure 9. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out.



7.9. Quad Output Fast Read (6BH)

The Quad Output Fast Read command is followed by 3-byte address (A23-A0) and a dummy byte, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 4-bit per clock cycle from IO3, IO2, IO1 and IO0. The command sequence is shown in followed Figure 10. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out.

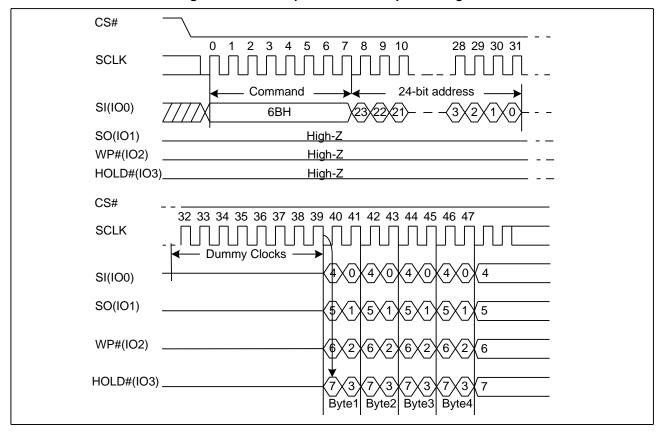


Figure 10. Quad Output Fast Read Sequence Diagram

7.10. Dual I/O Fast Read (BBH)

The Dual I/O Fast Read command is similar to the Dual Output Fast Read command but with the capability to input the 3-byte address (A23-0) and a "Continuous Read Mode" byte 2-bit per clock by SI and SO, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 2-bit per clock cycle from SI and SO. The command sequence is shown in followed Figure 11. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out.

Dual I/O Fast Read with "Continuous Read Mode"

The Dual I/O Fast Read command can further reduce command overhead through setting the "Continuous Read Mode" bits (M7-0) after the input 3-byte address (A23-A0). If the "Continuous Read Mode" bits (M7-0) =AXH, then the next Dual I/O Fast Read command (after CS# is raised and then lowered) does not require the BBH command code. The command sequence is shown in followed Figure11. If the "Continuous Read Mode" bits (M7-0) are any value other than AXH, the next command requires the first BBH command code, thus returning to normal operation. A "Continuous Read Mode" Reset command can be used to reset (M7-0) before issuing normal command.

Figure 11. Dual I/O Fast Read Sequence Diagram (M7-0= 0XH or not AXH)

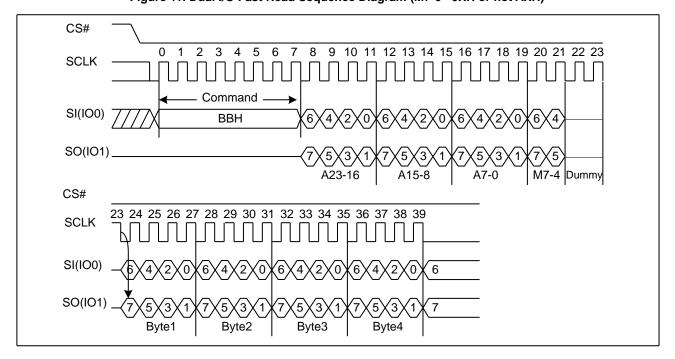
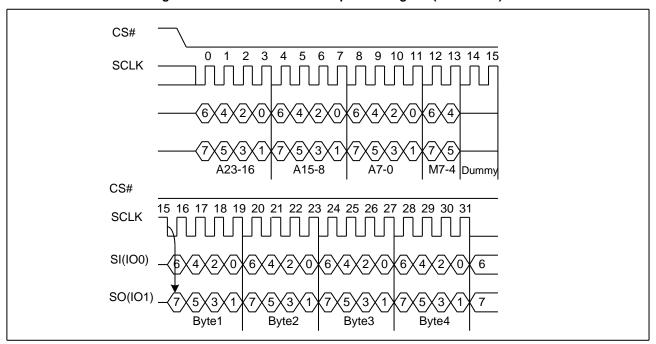


Figure 12. Dual I/O Fast Read Sequence Diagram (M7-0= AXH)



7.11. Quad I/O Fast Read (EBH)

The Quad I/O Fast Read command is similar to the Dual I/O Fast Read command but with the capability to input the 3-byte address (A23-0) and a "Continuous Read Mode" byte and 4-dummy clock 4-bit per clock by IO0, IO1, IO2, IO3, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 4-bit per clock cycle from IO0, IO1, IO2, IO3. The command sequence is shown in followed Figure 13. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out. The Quad Enable bit (QE) of Status Register (S9) must be set to enable for the Quad I/O Fast read command.

Quad I/O Fast Read with "Continuous Read Mode"

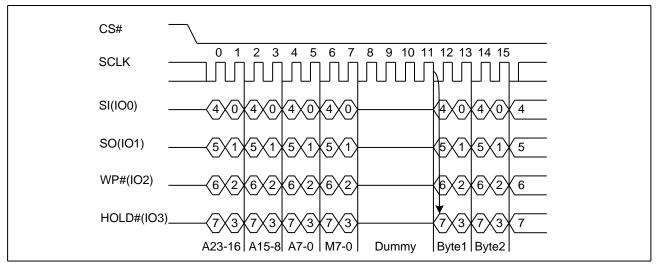
The Quad I/O Fast Read command can further reduce command overhead through setting the "Continuous Read Mode" bits (M7-0) after the input 3-byte address (A23-A0). If the "Continuous Read Mode" bits (M7-0) =AXH, then the next Quad I/O Fast Read command (after CS# is raised and then lowered) does not require the EBH command code. The command sequence is shown in followed Figure 13. If the "Continuous Read Mode" bits (M7-0) are any value other than AXH, the next command requires the first EBH command code, thus returning to normal operation. A "Continuous Read Mode" Reset command can be used to reset (M7-0) before issuing normal command.

Figure 13. Quad I/O Fast Read Sequence Diagram (M7-0= 0XH or not AXH)

Figure 14. Quad I/O Fast Read Sequence Diagram (M7-0= AXH)

A23-16 A15-8 A7-0 M7-0

Dummy



7.12. Quad I/O Word Fast Read (E7H)

The Quad I/O Word Fast Read command is similar to the Quad I/O Fast Read command except that the lowest address bit (A0) must equal 0 and only 2-dummy clock. The command sequence is shown in followed Figure 15. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out. The Quad Enable bit (QE) of Status Register (S9) must be set to enable for the Quad I/O Word Fast read command.

Quad I/O Word Fast Read with "Continuous Read Mode"

The Quad I/O Word Fast Read command can further reduce command overhead through setting the "Continuous Read Mode" bits (M7-0) after the input 3-byte address (A23-A0). If the "Continuous Read Mode" bits (M7-0) =AXH, then the next Quad I/O Word Fast Read command (after CS# is raised and then lowered) does not require the E7H command code. The command sequence is shown in followed Figure 15. If the "Continuous Read Mode" bits (M7-0) are any value other than AXH, the next command requires the first E7H command code, thus returning to normal operation. A "Continuous Read Mode" Reset command can be used to reset (M7-0) before issuing normal command.

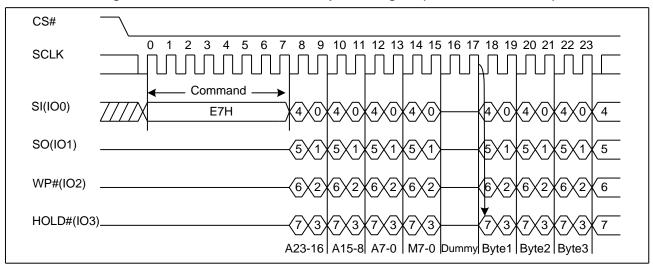
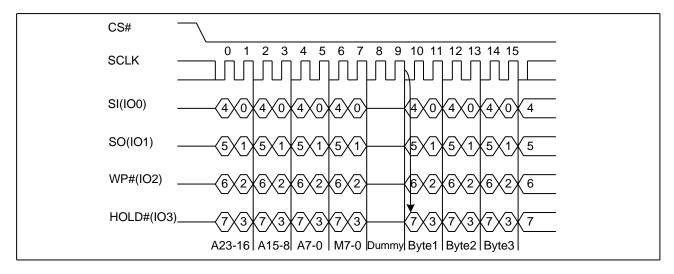


Figure 15. Quad I/O Word Fast Read Sequence Diagram (M7-0= 0XH or not AXH)

Figure 16. Quad I/O Word Fast Read Sequence Diagram (M7-0= AXH)



7.13. Set Burst with Wrap (77H)

The Set Burst with Wrap command is used in conjunction with "Quad I/O Fast Read" and "Quad I/O Word Fast Read" command to access a fixed length of 8/16/32/64-byte section within a 256-byte page, in standard SPI mode.

The Set Burst with Wrap command sequence: CS# goes low \rightarrow Send Set Burst with Wrap command \rightarrow Send 24 dummy bits \rightarrow Send 8 bits "Wrap bits" \rightarrow CS# goes high.

W6,W5	W4=0		W4=1 (default)		
	Wrap Around	Wrap Length	Wrap Around	Wrap Length	
0, 0	Yes	8-byte	No	N/A	
0, 1	Yes	16-byte	No	N/A	
1, 0	Yes	32-byte	No	N/A	
1, 1	Yes	64-byte	No	N/A	

If the W6-W4 bits are set by the Set Burst with Wrap command, all the following "Quad I/O Fast Read" and "Quad I/O Word Fast Read" command will use the W6-W4 setting to access the 8/16/32/64-byte section within any page. To exit the "Wrap Around" function and return to normal read operation, another Set Burst with Wrap command should be issued to set W4=1.

Figure 17. Set Burst with Wrap Sequence Diagram

7.14. Page Program (PP) (02H)

The Page Program (PP) command is for programming the memory. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit before sending the Page Program command.

The Page Program (PP) command is entered by driving CS# Low, followed by the command code, three address bytes and at least one data byte on SI. If the 8 least significant address bits (A7-A0) are not all zero, all transmitted data that goes beyond the end of the current page are programmed from the start address of the same page (from the address whose 8 least significant bits (A7-A0) are all zero). CS# must be driven low for the entire duration of the sequence. The Page Program command sequence: CS# goes low \rightarrow sending Page Program command \rightarrow 3-byte address on SI \rightarrow at least 1 byte data on SI \rightarrow CS# goes high. The command sequence is shown in Figure 18. If more than 256 bytes are sent to the device, previously latched data are discarded and the last 256 data bytes are guaranteed to be programmed correctly within the same page. If less than 256 data bytes are sent to device, they are correctly programmed at the requested addresses without having any effects on the other bytes of the same page. CS# must be driven high after the eighth bit of the last data byte has been latched in; otherwise the Page Program (PP) command is not executed.

As soon as CS# is driven high, the self-timed Page Program cycle (whose duration is tpp) is initiated. While the Page Program cycle is in progress, the Status Register may be read to check the value of the Write in Progress (WIP) bit. The Write in Progress (WIP) bit is 1 during the self-timed Page Program cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset.

A Page Program (PP) command applied to a page which is protected by the Block Protect (BP4, BP3, BP2, BP1, and BP0) is not executed.

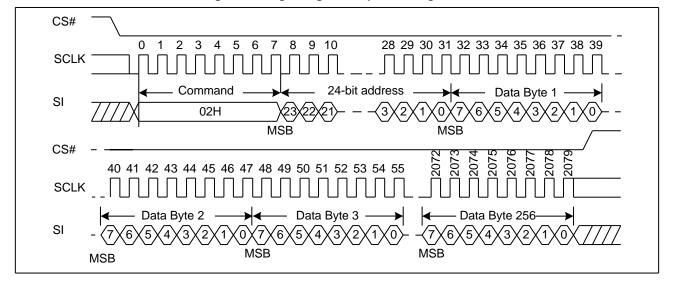


Figure 18. Page Program Sequence Diagram

7.15. Quad Page Program (32H)

The Quad Page Program command is for programming the memory using four pins: IO0, IO1, IO2, and IO3. To use Quad Page Program the Quad enable in status register Bit9 must be set (QE=1). A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit before sending the Page Program command. The quad Page Program command is entered by driving CS# Low, followed by the command code (32H), three address bytes and at least one data byte on IO pins.

The command sequence is shown in Figure 19. If more than 256 bytes are sent to the device, previously latched data are discarded and the last 256 data bytes are guaranteed to be programmed correctly within the same page. If less than 256 data bytes are sent to device, they are correctly programmed at the requested addresses without having any effects on the other bytes of the same page. CS# must be driven high after the eighth bit of the last data byte has been latched in; otherwise the Quad Page Program (PP) command is not executed.

As soon as CS# is driven high, the self-timed Quad Page Program cycle (whose duration is t_{PP}) is initiated. While the Quad Page Program cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write in Progress (WIP) bit is 1 during the self-timed Quad Page Program cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset.

A Quad Page Program command applied to a page which is protected by the Block Protect (BP4, BP3, BP2, BP1, and BP0) is not executed.

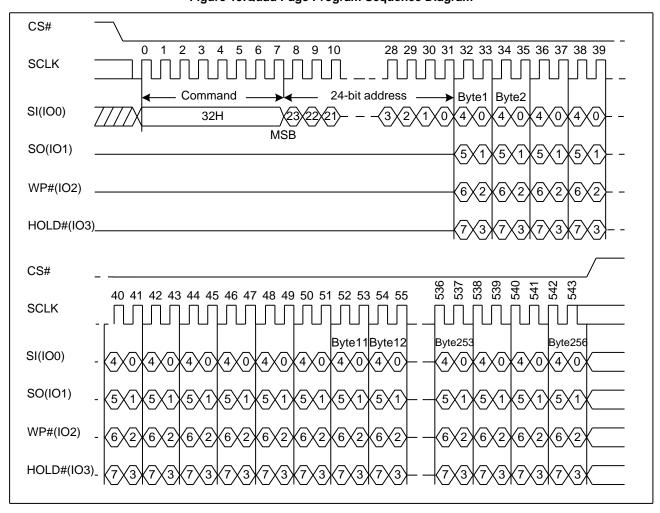


Figure 19.Quad Page Program Sequence Diagram

7.16. Sector Erase (SE) (20H)

The Sector Erase (SE) command is used to erase all the data of the chosen sector. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit. The Sector Erase (SE) command is entered by driving CS# low, followed by the command code, and 3-address byte on SI. Any address inside the sector is a valid address for the Sector Erase (SE) command. CS# must be driven low for the entire duration of the sequence.

The Sector Erase command sequence: CS# goes low \rightarrow sending Sector Erase command \rightarrow 3-byte address on SI \rightarrow CS# goes high. The command sequence is shown in Figure21. CS# must be driven high after the eighth bit of the last address byte has been latched in; otherwise the Sector Erase (SE) command is not executed. As soon as CS# is driven high, the self-timed Sector Erase cycle (whose duration is t_{SE}) is initiated. While the Sector Erase cycle is in progress, the Status Register may be read to check the value of the Write in Progress (WIP) bit. The Write in Progress (WIP) bit is 1 during the self-timed Sector Erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset. A Sector Erase (SE) command applied to a sector which is protected by the Block Protect (BP4, BP3, BP2, BP1, and BP0) bit (see Table1&1a) is not executed.

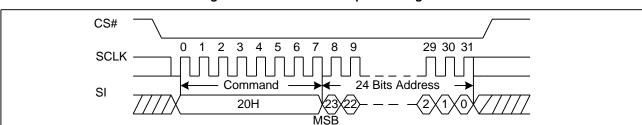


Figure 20. Sector Erase Sequence Diagram

7.17. 32KB Block Erase (BE) (52H)

The 32KB Block Erase (BE) command is used to erase all the data of the chosen block. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit. The 32KB Block Erase (BE) command is entered by driving CS# low, followed by the command code, and three address bytes on SI. Any address inside the block is a valid address for the 32KB Block Erase (BE) command. CS# must be driven low for the entire duration of the sequence.

The 32KB Block Erase command sequence: CS# goes low \rightarrow sending 32KB Block Erase command \rightarrow 3-byte address on SI \rightarrow CS# goes high. The command sequence is shown in Figure22. CS# must be driven high after the eighth bit of the last address byte has been latched in; otherwise the 32KB Block Erase (BE) command is not executed. As soon as CS# is driven high, the self-timed Block Erase cycle (whose duration is t_{BE}) is initiated. While the Block Erase cycle is in progress, the Status Register may be read to check the value of the Write in Progress (WIP) bit. The Write in Progress (WIP) bit is 1 during the self-timed Block Erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset. A 32KB Block Erase (BE) command applied to a block which is protected by the Block Protect (BP4, BP3, BP2, BP1, and BP0) bits (see Table1&1a) is not executed.

Figure 21. 32KB Block Erase Sequence Diagram

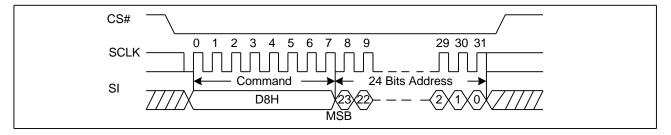
7.18. 64KB Block Erase (BE) (D8H)

The 64KB Block Erase (BE) command is used to erase all the data of the chosen block. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit. The 64KB Block Erase (BE) command is entered by driving CS# low, followed by the command code, and three address bytes on SI. Any address inside the block is a valid address for the 64KB Block Erase (BE) command. CS# must be driven low for the entire duration of the sequence.

The 64KB Block Erase command sequence: CS# goes low \rightarrow sending 64KB Block Erase command \rightarrow 3-byte address on SI \rightarrow CS# goes high. The command sequence is shown in Figure23. CS# must be driven high after the eighth bit of the last address byte has been latched in; otherwise the 64KB Block Erase (BE) command is not executed. As soon as CS# is driven high, the self-timed Block Erase cycle (whose duration is t_{BE}) is initiated. While the Block Erase cycle is in progress, the Status Register may be read to check the value of the Write in Progress (WIP) bit. The Write in Progress (WIP) bit is 1 during the self-timed Block Erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is

completed, the Write Enable Latch (WEL) bit is reset. A 64KB Block Erase (BE) command applied to a block which is protected by the Block Protect (BP4, BP3, BP2, BP1, and BP0) bits (see Table1&1a) is not executed.

Figure 22. 64KB Block Erase Sequence Diagram

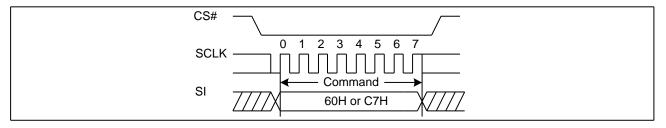


7.19. Chip Erase (CE) (60/C7H)

The Chip Erase (CE) command is used to erase all the data of the chip. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit .The Chip Erase (CE) command is entered by driving CS# Low, followed by the command code on Serial Data Input (SI). CS# must be driven Low for the entire duration of the sequence.

The Chip Erase command sequence: CS# goes low \rightarrow sending Chip Erase command \rightarrow CS# goes high. The command sequence is shown in Figure21. CS# must be driven high after the eighth bit of the command code has been latched in; otherwise the Chip Erase command is not executed. As soon as CS# is driven high, the self-timed Chip Erase cycle (whose duration is t_{CE}) is initiated. While the Chip Erase cycle is in progress, the Status Register may be read to check the value of the Write in Progress (WIP) bit. The Write in Progress (WIP) bit is 1 during the self-timed Chip Erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset. The Chip Erase (CE) command is executed only if all Block Protect (BP2, BP1, and BP0) bits are 0. The Chip Erase (CE) command is ignored if one or more sectors are protected.

Figure 23. Chip Erase Sequence Diagram



7.20. Deep Power-Down (DP) (B9H)

Executing the Deep Power-Down (DP) command is the only way to put the device in the lowest consumption mode (the Deep Power-Down Mode). It can also be used as an extra software protection mechanism, while the device is not in active use, since in this mode, the device ignores all Write, Program and Erase commands. Driving CS# high deselects the device, and puts the device in the Standby Mode (if there is no internal cycle currently in progress). But this mode is not the Deep Power-Down Mode. The Deep Power-Down Mode can only be entered by executing the Deep Power-Down (DP) command. Once the device has entered the Deep Power-Down Mode, all commands are ignored except the Release from Deep Power-Down and Read Device ID (RDI) command. This releases the device from this mode. The Release from Deep Power-Down and Read Device ID (RDI) command also allows the Device ID of the device to be output on SO.

The Deep Power-Down Mode automatically stops at Power-Down, and the device always Power-Up in the Standby Mode. The Deep Power-Down (DP) command is entered by driving CS# low, followed by the command code on SI. CS# must be driven low for the entire duration of the sequence.

The Deep Power-Down command sequence: CS# goes low \rightarrow sending Deep Power-Down command \rightarrow CS# goes high. The command sequence is shown in Figure 22. CS# must be driven high after the eighth bit of the command code has been latched in; otherwise the Deep Power-Down (DP) command is not executed. As soon as CS# is driven high, it requires a delay of t_{DP} before the supply current is reduced to I_{CC2} and the Deep Power-Down Mode is entered. Any Deep Power-Down (DP) command, while an Erase, Program or Write cycle is in progress, is rejected without having any effects on the cycle that is in progress.

SCLK 0 1 2 3 4 5 6 7

SCLK Command Stand-by mode Deep Power-down mode

B9H

Figure 24. Deep Power-Down Sequence Diagram

7.21. Release from Deep Power-Down or High Performance Mode and Read Device ID (RDI) (ABH)

The Release from Power-Down or High Performance Mode / Device ID command is a multi-purpose command. It can be used to release the device from the Power-Down state or High Performance Mode or obtain the devices electronic identification (ID) number.

To release the device from the Power-Down state or High Performance Mode, the command is issued by driving the CS# pin low, shifting the instruction code "ABH" and driving CS# high as shown in Figure26. Release from Power-Down will take the time duration of t_{RES1} (See AC Characteristics) before the device will resume normal operation and other command are accepted. The CS# pin must remain high during the t_{RES1} time duration.

When used only to obtain the Device ID while not in the Power-Down state, the command is initiated by driving the CS# pin low and shifting the instruction code "ABH" followed by 3-dummy byte. The Device ID bits are then shifted out on the falling edge of SCLK with most significant bit (MSB) first as shown in Figure 27. The Device ID value is listed in Manufacturer and Device Identification table. The Device ID can be read continuously. The command is completed by driving CS# high.

When used to release the device from the Power-Down state and obtain the Device ID, the command is the same as previously described, and shown in Figure27, except that after CS# is driven high it must remain high for a time duration of t_{RES2} (See AC Characteristics). After this time duration the device will resume normal operation and other command will be accepted. If the Release from Power-Down / Device ID command is issued while an Erase, Program or Write cycle is in process (when WIP equal 1) the command is ignored and will not have any effects on the current cycle.

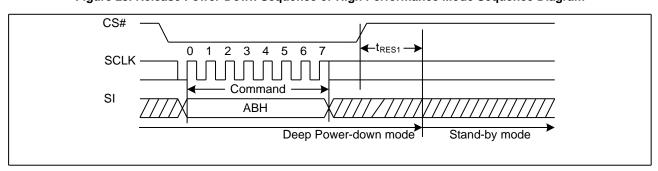


Figure 25. Release Power-Down Sequence or High Performance Mode Sequence Diagram

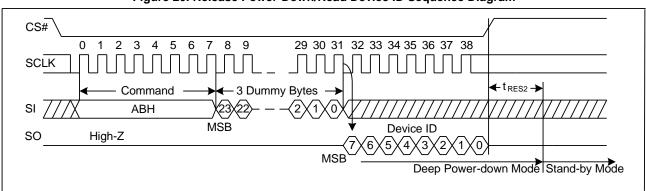


Figure 26. Release Power-Down/Read Device ID Sequence Diagram

7.22. Read Manufacture ID/ Device ID (REMS) (90H)

The Read Manufacturer/Device ID command is an alternative to the Release from Power-Down / Device ID command that provides both the JEDEC assigned Manufacturer ID and the specific Device ID.

The command is initiated by driving the CS# pin low and shifting the command code "90H" followed by a 24-bit address (A23-A0) of 000000H. After which, the Manufacturer ID and the Device ID are shifted out on the falling edge of SCLK with most significant bit (MSB) first as shown in Figure 28. If the 24-bit address is initially set to 000001H, the Device ID will be read first.

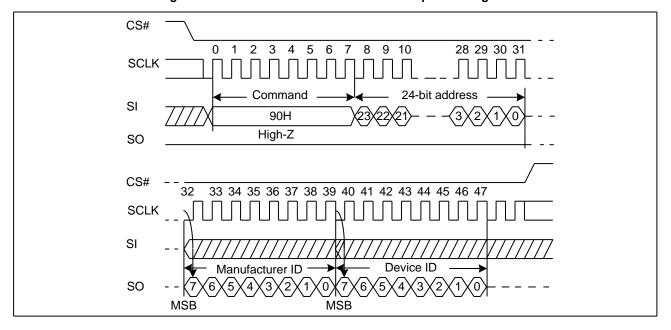


Figure 27. Read Manufacture ID/ Device ID Sequence Diagram

7.23. Read Identification (RDID) (9FH)

The Read Identification (RDID) command allows the 8-bit manufacturer identification to be read, followed by two bytes of device identification. The device identification indicates the memory type in the first byte, and the memory capacity of the device in the second byte. The Read Identification (RDID) command while an Erase or Program cycle is in progress is not decoded, and has no effect on the cycle that is in progress. The Read Identification (RDID) command should not be issued while the device is in Deep Power-Down Mode.

The device is first selected by driving CS# to low. Then, the 8-bit command code for the command is shifted in. This is followed by the 24-bit device identification, stored in the memory, being shifted out on Serial Data Output, each bit being shifted out during the falling edge of Serial Clock. The command sequence is shown in Figure 31. The Read Identification (RDID) command is terminated by driving CS# to high at any time during data output. When CS# is driven high, the device is put in the Standby Mode. Once in the Standby Mode, the device waits to be selected, so that it can receive, decode and execute commands.

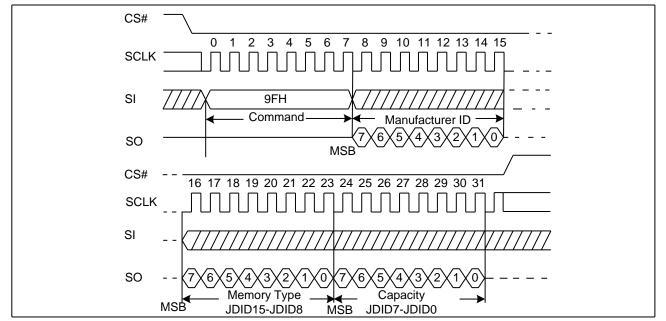
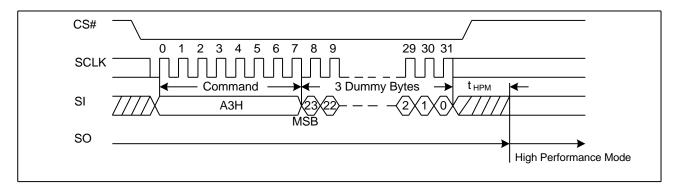


Figure 28. Read Identification ID Sequence Diagram

7.24. High Performance Mode (HPM) (A3H)

The High Performance Mode (HPM) command must be executed prior to Dual or Quad I/O commands when operating at high frequencies (see fc₂ and fc₃ in AC Electrical Characteristics). This command allows pre-charging of internal charge pumps so the voltages required for accessing the flash memory array are readily available. The command sequence: CS# goes Iow→Sending A3H command→ Sending 3-dummy byte→CS# goes high. See Figure32. After the HPM command is executed, the device will maintain a slightly higher standby current (Icc8) than standard SPI operation. The Release from Power-Down or HPM command (ABH) can be used to return to standard SPI standby current (Icc1). In addition, Power-Down command (B9H) will also release the device from HPM mode back to standard SPI standby state.

Figure 29. High Performance Mode Sequence Diagram

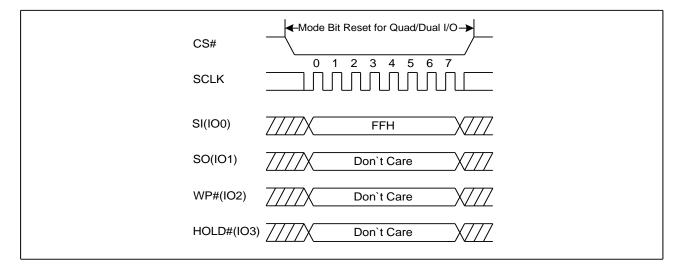


7.25. Continuous Read Mode Reset (CRMR) (FFH)

The Dual/Quad I/O Fast Read operations, "Continuous Read Mode" bits (M7-0) are implemented to further reduce command overhead. By setting the (M7-0) to AXH, the next Dual/Quad I/O Fast Read operations do not require the BBH/EBH/E7H command code.

Because the GD25Q40C has no hardware reset pin, so if Continuous Read Mode bits are set to "AXH", the GD25Q40C will not recognize any standard SPI commands. So Continuous Read Mode Reset command will release the Continuous Read Mode from the "AXH" state and allow standard SPI command to be recognized. The command sequence is show in Figure 28.

Figure 30. Continuous Read Mode Reset Sequence Diagram



7.26. Read Unique ID (4BH)

The Read Unique ID command accesses a factory-set read-only 128bit number that is unique to each device. The Unique ID can be used in conjunction with user software methods to help prevent copying or cloning of a system.

The Read Unique ID command sequence: CS# goes low \rightarrow sending Read Unique ID command \rightarrow 3-Byte Address (000000H) \rightarrow Dummy Byte \rightarrow 128bit Unique ID Out \rightarrow CS# goes high.

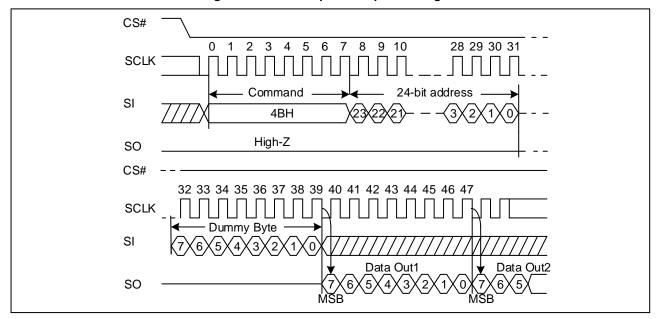


Figure 31. Read Unique ID Sequence Diagram

7.27. Program/Erase Suspend (PES) (75H)

The Program/Erase Suspend command "75H", allows the system to interrupt a page program or sector/block erase operation and then read data from any other sector or block. The Write Status Register command (01H) and Erase/Program Security Registers command (44H, 42H) and Erase commands (20H, 52H, D8H, C7H, 60H) and Page Program command (02H / 32H) are not allowed during Program/Erase suspend. Program/Erase Suspend is valid only during the page program or sector/block erase operation. A maximum of time of "tsus" (See AC Characteristics) is required to suspend the program/erase operation.

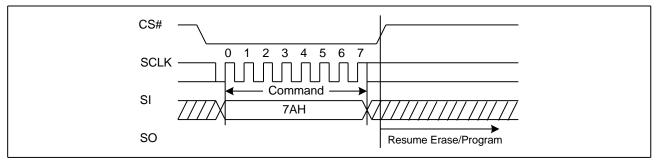
The Program/Erase Suspend command will be accepted by the device only if the SUS bit in the Status Register equal to 0 and WIP bit equal to 1 while a Page Program or a Sector or Block Erase operation is on-going. If the SUS bit equal to 1 or WIP bit equal to 0, the Suspend command will be ignored by the device. The WIP bit will be cleared from 1 to 0 within "tsus" and the SUS bit will be set from 0 to 1 immediately after Program/Erase Suspend. A power-off during the suspend period will reset the device and release the suspend state. The command sequence is show in Figure 30.

Figure 32. Program/Erase Suspend Sequence Diagram

7.28. Program/Erase Resume (PER) (7AH)

The Program/Erase Resume command must be written to resume the program or sector/block erase operation after a Program/Erase Suspend command. The Program/Erase Resume command will be accepted by the device only if the SUS bit equal to 1 and the WIP bit equal to 0. After issued the SUS bit in the status register will be cleared from 1 to 0 immediately, the WIP bit will be set from 0 to 1 within 200ns and the Sector or Block will complete the erase operation or the page will complete the program operation. The Program/Erase Resume command will be ignored unless a Program/Erase Suspend is active. The command sequence is show in Figure31.

Figure 33. Program/Erase Resume Sequence Diagram



7.29. Erase Security Registers (44H)

The GD25Q40C provides four 256-byte Security Registers which can be read and programmed individually. These registers may be used by the system manufacturers to store security and other important information separately from the main memory array.

The Erase Security Registers command is similar to Sector/Block Erase command. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit.

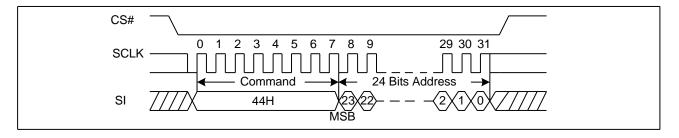
The Erase Security Registers command sequence: CS# goes low → sending Erase Security Registers command → CS# goes high. The command sequence is shown in Figure31. CS# must be driven high after the eighth bit of the command code has been latched in, otherwise the Erase Security Registers command is not executed. As soon as CS# is driven high, the self-timed Erase Security Registers cycle (whose duration is t_{SE}) is initiated. While the Erase Security Registers cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Erase Security Registers cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset. The Security Registers Lock Bit (LB) in the Status Register can be used to OTP protect the security registers. Once the LB bit is set to 1, the Security Registers will be permanently locked; the Erase Security Registers command will be ignored.

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GD25Q40C

Address		A23-A16	A15-A8	A7-A0
	Security Registers	00000000	00000000	Don't Care

Figure 34. Erase Security Registers command Sequence Diagram



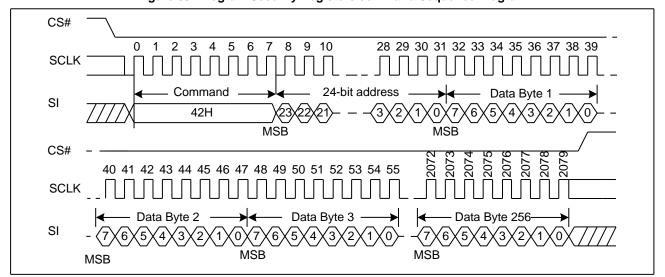
7.30. Program Security Registers (42H)

The Program Security Registers command is similar to the Page Program command. It allows from 1 to 256 bytes Security Registers data to be programmed. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit before sending the Program Security Registers command. The Program Security Registers command is entered by driving CS# Low, followed by the command code (42H), three address bytes and at least one data byte on SI. As soon as CS# is driven high, the self-timed Program Security Registers cycle (whose duration is tPP) is initiated. While the Program Security Registers cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Program Security Registers cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset.

If the Security Registers Lock Bit (LB) is set to 1, the Security Registers will be permanently locked. Program Security Registers command will be ignored.

Address	A23-A16	A15-A8	A7-A0
Security Registers 0	00H	00H	Byte Address
Security Registers 1	00H	01H	Byte Address
Security Registers 2	00H	02H	Byte Address
Security Registers 3	00H	03H	Byte Address

Figure 35. Program Security Registers command Sequence Diagram

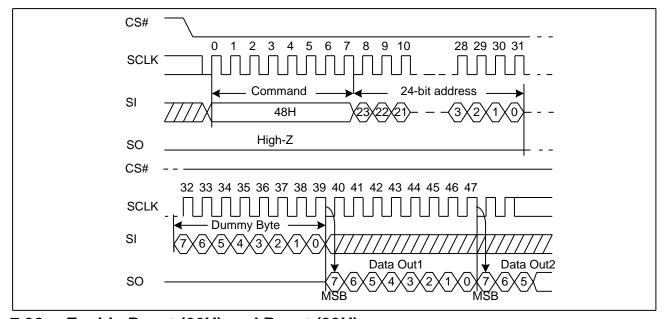


7.31. Read Security Registers (48H)

The Read Security Registers command is similar to Fast Read command. The command is followed by a 3-byte address (A23-A0) and a dummy byte, each bit being latched-in during the rising edge of SCLK. Then the memory content, at that address, is shifted out on SO, each bit being shifted out, at a Max frequency fC, during the falling edge of SCLK. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out. Once the A7-A0 address reaches the last byte of the register (Byte FFH), it will reset to 00H, the command is completed by driving CS# high.

Address	A23-A16	A15-A8	A7-A0
Security Registers 0	00H	00H	Byte Address
Security Registers 1	00H	01H	Byte Address
Security Registers 2	00H	02H	Byte Address
Security Registers 3	00H	03H	Byte Address

Figure 36. Read Security Registers command Sequence Diagram

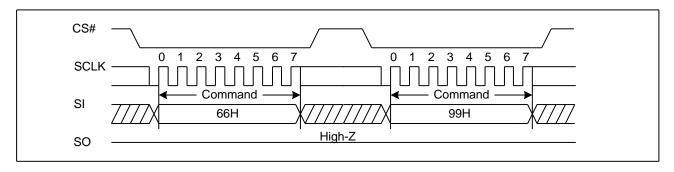


7.32. Enable Reset (66H) and Reset (99H)

If the Reset command is accepted, any on-going internal operation will be terminated and the device will return to its default power-on state and lose all the current volatile settings, such as Volatile Status Register bits, Write Enable Latch status (WEL), Program/Erase Suspend status, Read Parameter setting (P7-P0), Continuous Read Mode bit setting (M7-M0) and Wrap Bit Setting (W6-W4).

The "Reset (99H)" command sequence as follow: CS# goes low \rightarrow Sending Enable Reset command \rightarrow CS# goes high \rightarrow CS# goes low \rightarrow Sending Reset command \rightarrow CS# goes high. Once the Reset command is accepted by the device, the device will take approximately $t_{RST/E}$ to reset. During this period, no command will be accepted. Data corruption may happen if there is an on-going or suspended internal Erase or Program operation when Reset command sequence is accepted by the device. It is recommended to check the BUSY bit and the SUS bit in Status Register before issuing the Reset command sequence.

Figure 37. Enable Reset and Reset command Sequence Diagram



7.33. Read Serial Flash Discoverable Parameter (5AH)

The Serial Flash Discoverable Parameter (SFDP) standard provides a consistent method of describing the functional and feature capabilities of serial flash devices in a standard set of internal parameter tables. These parameter tables can be interrogated by host system software to enable adjustments needed to accommodate divergent features from multiple vendors. The concept is similar to the one found in the Introduction of JEDEC Standard, JESD68 on CFI. SFDP is a standard of JEDEC Standard No.216.

Figure 38. Read Serial Flash Discoverable Parameter command Sequence Diagram

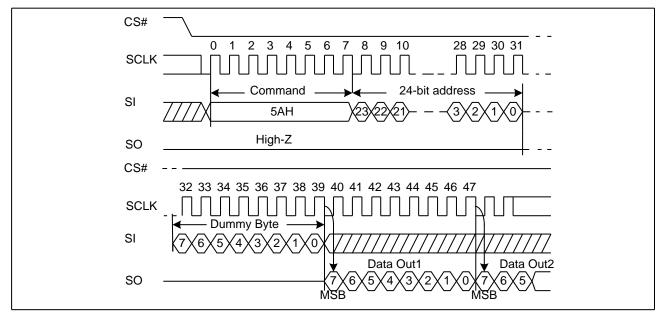




Table3. Signature and Parameter Identification Data Values

Description	Comment	Add(H) (Byte)	DW Add (Bit)	Data	Data
SFDP Signature	Fixed:50444653H	00H	07:00	53H	53H
or an engineering		01H	15:08	46H	46H
		02H	23:16	44H	44H
		03H	31:24	50H	50H
SFDP Minor Revision Number	Start from 00H	04H	07:00	00H	00H
SFDP Major Revision Number	Start from 01H	05H	15:08	01H	01H
Number of Parameters Headers	Start from 00H	06H	23:16	01H	01H
Unused	Contains 0xFFH and can never	07H	31:24	FFH	FFH
Chased	be changed	0711	01.24	1111	1111
ID number (JEDEC)	00H: It indicates a JEDEC	08H	07:00	00H	00H
	specified header				
Parameter Table Minor Revision	Start from 0x00H	09H	15:08	00H	00H
Number					
Parameter Table Major Revision	Start from 0x01H	0AH	23:16	01H	01H
Number					
Parameter Table Length	How many DWORDs in the	0BH	31:24	09H	09H
(in double word)	Parameter table				
Parameter Table Pointer (PTP)	First address of JEDEC Flash	0CH	07:00	30H	30H
	Parameter table	0DH	15:08	00H	00H
		0EH	23:16	00H	00H
Unused	Contains 0xFFH and can never	0FH	31:24	FFH	FFH
	be changed				
ID Number	It is indicates GigaDevice	10H	07:00	C8H	C8H
(GigaDevice Manufacturer ID)	manufacturer ID				
Parameter Table Minor Revision	Start from 0x00H	11H	15:08	00H	00H
Number					
Parameter Table Major Revision	Start from 0x01H	12H	23:16	01H	01H
Number					
Parameter Table Length	How many DWORDs in the	13H	31:24	03H	03H
(in double word)	Parameter table				
Parameter Table Pointer (PTP)	First address of GigaDevice Flash	14H	07:00	60H	60H
	Parameter table	15H	15:08	00H	00H
		16H	23:16	00H	00H
Unused	Contains 0xFFH and can never	17H	31:24	FFH	FFH
	be changed				

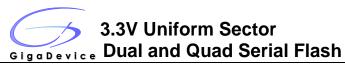


Table4. Parameter Table (0): JEDEC Flash Parameter Tables

Block/Sector Erase Size	Description	Parameter Table (0): JEDEC Flash Comment	Add(H)	DW Add	Data	Data	
Block/Sector Erase Size	Boomption	Commone	` ,		Data	Data	
Block/Sector Erase Size		00: Reserved: 01: 4KB erase:	(2)(0)	(511)			
11: not support 4KB erase	Block/Sector Frase Size	,		01:00	01h		
Write Granularity 0: 1Byte, 1: 64Byte or larger Write Enable Instruction 0: Nonvolatile status bit Requested for Writing to Volatile 1: Volatile status bit Status Registers (BP status register bit) 0: Use 50H Opcode, 30H Write Enable Opcode Select for 1: Use 06H Opcode, Writing to Volatile Status Note: If target flash status register is Nonvolatile, then bits 3 and 4 must be set to 00b. Unused Contains 111b and can never be changed 4KB Erase Opcode 31H (1-1-2) Fast Read 0=Not support, 1=Support Address Bytes Number used in addressing flash array 00: 3Byte only, 01: 3 or 4Byte, 10: 4Byte only, 11: Reserved Double Transfer Rate (DTR) clocking 0=Not support, 1=Support (1-2-2) Fast Read 0=Not support, 1=Support (1-4-4) Fast Read 0=Not support, 1=Support (1-4-4) Fast Read 0=Not support, 1=Support Unused 20 1b 22 1b 22 1b 23 1b 23 1b 22 1b 23 1b	Discit Costs: Liaco Sizo	,		01.00	010		
Write Enable Instruction 0: Nonvolatile status bit Requested for Writing to Volatile 1: Volatile status bit Status Registers (BP status register bit) 0: Use 50H Opcode, 30H Write Enable Opcode Select for Writing to Volatile Status Note: If target flash status register is Nonvolatile, then bits 3 and 4 must be set to 00b. Unused Contains 111b and can never be changed 4KB Erase Opcode 31H (1-1-2) Fast Read 0=Not support, 1=Support Address Bytes Number used in addressing flash array 10: 4Byte only, 11: Reserved Double Transfer Rate (DTR) clocking 0=Not support, 1=Support (1-2-2) Fast Read 0=Not support, 1=Support (1-2-2) Fast Read 0=Not support, 1=Support (1-2-4) Fast Read 0=Not support, 1=Support (1-2-4) Fast Read 0=Not support, 1=Support Unused 20 1b 22 21 1b Unused 33H 31:24 File File (1-4-4) Fast Read Number of 0 0000b: Wait states (Dummy (1-4-4) Fast Read Number of 0 0000b: Wait states (Dummy <t< td=""><td>Write Granularity</td><td></td><td></td><td>02</td><td>1b</td><td></td></t<>	Write Granularity			02	1b		
Requested for Writing to Volatile Status Registers (BP status register bit) (BP status registe				02	1.0		
Status Registers (BP status register bit) 0: Use 50H Opcode, 1: Use 06H Opcode, 1: Use 06H Opcode, Note: If target flash status register is Nonvolatile, then bits 3 and 4 must be set to 00b.				03	0b		
Write Enable Opcode Select for 1: Use 06H Opcode, 1: Use 06H Opcode, Note: If target flash status register is Nonvolatile, then bits 3 and 4 must be set to 00b.	•			00	0.0		
Write Enable Opcode Select for Writing to Volatile Status 1: Use 06H Opcode, Note: If target flash status register is Nonvolatile, then bits 3 and 4 must be set to 00b. 04 0b Unused Contains 111b and can never be changed 07:05 111b 4KB Erase Opcode 31H 15:08 20H 20 (1-1-2) Fast Read 0=Not support, 1=Support 16 1b 1b Address Bytes Number used in addressing flash array 10: 4Byte only, 01: 3 or 4Byte, 10: 4Byte only, 11: Reserved 18:17 00b 0b Double Transfer Rate (DTR) clocking 0=Not support, 1=Support 19 0b 1b 1c 1c <t< td=""><td>- Comment of Green</td><td></td><td>30H</td><td></td><td></td><td>E5H</td></t<>	- Comment of Green		30H			E5H	
Writing to Volatile Status Note: If target flash status register is Nonvolatile, then bits 3 and 4 must be set to 00b. 04 0b Unused Contains 111b and can never be changed 07:05 111b 4KB Erase Opcode 31H 15:08 20H 20 (1-1-2) Fast Read 0=Not support, 1=Support 16 1b 1b Address Bytes Number used in addressing flash array 10: 4Byte only, 01: 3 or 4Byte, 10: 4Byte only, 11: Reserved 18:17 00b 0b Double Transfer Rate (DTR) clocking 0=Not support, 1=Support 32H 19 0b 0b 1b 1b 1c 1c 1c 1c 1b 1c	Write Enable Opcode Select for	•					
Registers is Nonvolatile, then bits 3 and 4 must be set to 00b.	·	• •		04	0b		
Unused Contains 111b and can never be changed 07:05 111b 4KB Erase Opcode 31H 15:08 20H 20 (1-1-2) Fast Read 0=Not support, 1=Support 16 1b Address Bytes Number used in addressing flash array 10: 4Byte only, 01: 3 or 4Byte, 10: 4Byte only, 11: Reserved 19 18:17 00b Double Transfer Rate (DTR) 0=Not support, 1=Support 20 1b (1-2-2) Fast Read 0=Not support, 1=Support 21 1b (1-4-4) Fast Read 0=Not support, 1=Support 22 1b Unused 33H 31:24 FFH FF Flash Memory Density 37H:34H 31:00 003FFFFH (1-4-4) Fast Read Number of Wait states (Dummy Clocks) not support 38H (1-4-4) Fast Read Number of 000b:Mode Bits not support 07:05 010b	-						
Unused changed 07:05 111b 4KB Erase Opcode 31H 15:08 20H 20 (1-1-2) Fast Read 0=Not support, 1=Support 16 1b Address Bytes Number used in addressing flash array 00: 3Byte only, 01: 3 or 4Byte, 10: 4Byte only, 11: Reserved 18:17 00b Double Transfer Rate (DTR) clocking 0=Not support, 1=Support 19 0b 19 (1-2-2) Fast Read 0=Not support, 1=Support 20 1b 1b (1-4-4) Fast Read 0=Not support, 1=Support 21 1b (1-1-4) Fast Read 0=Not support, 1=Support 22 1b Unused 33H 31:24 FFH FF Flash Memory Density 37H:34H 31:00 003FFFFFH (1-4-4) Fast Read Number of 0 0000b: Wait states (Dummy 04:00 00100b Wait states Clocks) not support 38H 07:05 010b		must be set to 00b.					
Changed 31H 15:08 20H 20		Contains 111b and can never be		07:05		4441	
(1-1-2) Fast Read 0=Not support, 1=Support 16 1b Address Bytes Number used in addressing flash array 00: 3Byte only, 01: 3 or 4Byte, 10: 4Byte only, 11: Reserved 18:17 00b Double Transfer Rate (DTR) clocking 0=Not support, 1=Support 19 0b 15 (1-2-2) Fast Read 0=Not support, 1=Support 20 1b (1-4-4) Fast Read 0=Not support, 1=Support 21 1b (1-1-4) Fast Read 0=Not support, 1=Support 22 1b Unused 23 1b Unused 33H 31:24 FFH FF Flash Memory Density 37H:34H 31:00 003FFFFFH (1-4-4) Fast Read Number of Wait states 0 0000b: Wait states (Dummy Clocks) not support 38H 04:00 00100b (1-4-4) Fast Read Number of Wait states Read Number of States (Dummy Clocks) not support 0000b: Mode Bits not support 07:05 010b	Unused	changed			111b		
Address Bytes Number used in addressing flash array 00: 3Byte only, 01: 3 or 4Byte, 10: 4Byte only, 11: Reserved 18:17 00b Double Transfer Rate (DTR) clocking 0=Not support, 1=Support 19 0b 15 (1-2-2) Fast Read 0=Not support, 1=Support 20 1b 20 1b (1-4-4) Fast Read 0=Not support, 1=Support 21 1b 22 1b Unused 0=Not support, 1=Support 22 1b 23 1b Unused 33H 31:24 FFH FF Flash Memory Density 37H:34H 31:00 003FFFFH (1-4-4) Fast Read Number of Wait states Clocks) not support 38H 04:00 00100b (1-4-4) Fast Read Number of Wait states 000b:Mode Bits not support 07:05 010b	4KB Erase Opcode		31H	15:08	20H	20H	
10: 4Byte only, 11: Reserved 18:17 00b	(1-1-2) Fast Read	0=Not support, 1=Support		16	1b		
Double Transfer Rate (DTR)	Address Bytes Number used in	00: 3Byte only, 01: 3 or 4Byte,		10.17	0.01		
Clocking	addressing flash array	10: 4Byte only, 11: Reserved		18:17	00b		
Clocking 32H 51	Double Transfer Rate (DTR)	O Net consent 4 Occurrent		40	Ol-		
(1-4-4) Fast Read 0=Not support, 1=Support 21 1b (1-1-4) Fast Read 0=Not support, 1=Support 22 1b Unused 23 1b Unused 33H 31:24 FFH FF Flash Memory Density 37H:34H 31:00 003FFFFFH (1-4-4) Fast Read Number of Wait states 0 0000b: Wait states (Dummy Clocks) not support 04:00 00100b (1-4-4) Fast Read Number of O00b: Mode Bits not support 07:05 010b	clocking	U=Not support, 1=Support	32H	19	du	F1H	
(1-1-4) Fast Read 0=Not support, 1=Support 22 1b Unused 23 1b Unused 33H 31:24 FFH FF Flash Memory Density 37H:34H 31:00 003FFFFFH (1-4-4) Fast Read Number of Wait states 0 0000b: Wait states (Dummy Clocks) not support 04:00 00100b (1-4-4) Fast Read Number of (1-4-4) Fast Rea	(1-2-2) Fast Read	0=Not support, 1=Support		20	1b		
Unused 23 1b Unused 33H 31:24 FFH FF Flash Memory Density 37H:34H 31:00 003FFFFH (1-4-4) Fast Read Number of Wait states 0 0000b: Wait states (Dummy Clocks) not support 04:00 00100b (1-4-4) Fast Read Number of (1-4-4) F	(1-4-4) Fast Read	0=Not support, 1=Support		21	1b		
Unused 33H 31:24 FFH FF Flash Memory Density 37H:34H 31:00 003FFFFFH (1-4-4) Fast Read Number of Wait states 0 0000b: Wait states (Dummy Clocks) not support 04:00 00100b (1-4-4) Fast Read Number of (1-4-4)	(1-1-4) Fast Read	0=Not support, 1=Support		22	1b		
Flash Memory Density 37H:34H 31:00 003FFFFFH (1-4-4) Fast Read Number of Wait states 0 0000b: Wait states (Dummy Clocks) not support 04:00 00100b (1-4-4) Fast Read Number of (1-4-4) Fast Read Numbe	Unused			23	1b		
(1-4-4) Fast Read Number of U 0000b: Wait states (Dummy O4:00 00100b O100b O10	Unused		33H	31:24	FFH	FFH	
Wait states Clocks) not support 38H 04:00 00100b (1-4-4) Fast Read Number of 000b:Mode Bits not support 07:05 010b	Flash Memory Density		37H:34H	31:00	003FFF	FFH	
Wait states Clocks) not support 38H 04:00 00100b (1-4-4) Fast Read Number of 000b:Mode Bits not support 07:05 010b	(1-4-4) Fast Read Number of	0 0000b: Wait states (Dummy					
(1-4-4) Fast Read Number of 000b:Mode Bits not support 07:05 010b	` ,			04:00	00100b		
000b:Mode Bits not support 07:05 010b	(1-4-4) Fast Read Number of		38H			44H	
	Mode Bits	000b:Mode Bits not support		07:05	010b		
(1-4-4) Fast Read Opcode 39H 15:08 EBH EE	(1-4-4) Fast Read Opcode		39H	15:08	EBH	EBH	
(1-1-4) Fast Read Number of 0 0000b: Wait states (Dummy	(1-1-4) Fast Read Number of	0 0000b: Wait states (Dummy		00.15	0.4.0.5.5		
Wait states Clocks) not support 20:16 01000b	Wait states	Clocks) not support	641.	20:16	01000b	661:	
(1-1-4) Fast Read Number of	(1-1-4) Fast Read Number of	OOOL-Marda Dita ii	3AH	00.04	0001	08H	
Mode Bits 000b:Mode Bits not support 23:21 000b	Mode Bits	UUUD:Mode Bits not support		23:21	0006		
(1-1-4) Fast Read Opcode 3BH 31:24 6BH 6E	(1-1-4) Fast Read Opcode		звн	31:24	6BH	6BH	



3.3V Uniform Sector Gigabevice Dual and Quad Serial Flash

GD25Q40C

(2-2-2) Fast Read 0=not support 1=support 00 0b Unused 03:01 111b	Data 08H 3BH 42H BBH
Wait states Clocks) not support 3CH 04:00 01000b (1-1-2) Fast Read Number of Mode Bits 000b: Mode Bits not support 07:05 000b (1-1-2) Fast Read Opcode 3DH 15:08 3BH (1-2-2) Fast Read Number of Wait states 0 0000b: Wait states (Dummy Clocks) not support 20:16 00010b (1-2-2) Fast Read Number of Mode Bits 000b: Mode Bits not support 3EH 23:21 010b (1-2-2) Fast Read Opcode 3FH 31:24 BBH (2-2-2) Fast Read 0=not support 1=support 00 0b Unused 03:01 111b	3BH 42H BBH
(1-1-2) Fast Read Number of Mode Bits 000b: Mode Bits not support 07:05 000b (1-1-2) Fast Read Opcode 3DH 15:08 3BH (1-2-2) Fast Read Number of Wait states 0 0000b: Wait states (Dummy Clocks) not support 20:16 00010b (1-2-2) Fast Read Number of Mode Bits 000b: Mode Bits not support 3EH 23:21 010b (1-2-2) Fast Read Opcode 3FH 31:24 BBH (2-2-2) Fast Read 0=not support 1=support 00 0b Unused 03:01 111b	3BH 42H BBH
(1-2-2) Fast Read Number of Wait states 0 0000b: Wait states (Dummy Clocks) not support 20:16 00010b (1-2-2) Fast Read Number of Mode Bits 000b: Mode Bits not support 23:21 010b (1-2-2) Fast Read Opcode 3FH 31:24 BBH (2-2-2) Fast Read 0=not support 1=support 00 0b Unused 03:01 111b	42H BBH
of Wait states Clocks) not support 3EH 20:16 00010b (1-2-2) Fast Read Number of Mode Bits 000b: Mode Bits not support 23:21 010b (1-2-2) Fast Read Opcode 3FH 31:24 BBH (2-2-2) Fast Read 0=not support 1=support 00 0b Unused 03:01 111b	ВВН
(1-2-2) Fast Read Number of Mode Bits 000b: Mode Bits not support 23:21 010b (1-2-2) Fast Read Opcode 3FH 31:24 BBH (2-2-2) Fast Read 0=not support 1=support 00 0b Unused 03:01 111b	ВВН
(2-2-2) Fast Read 0=not support 1=support 00 0b Unused 03:01 111b	
Unused 03:01 111b	EEH
40H	EEH
	EEM
(4-4-4) Fast Read 0=not support 1=support 04 0b	
Unused 07:05 111b	
Unused 43H:41H 31:08 0xFFH (0xFFH
Unused 45H:44H 15:00 0xFFH 0	0xFFH
(2-2-2) Fast Read Number 0 0000b: Wait states (Dummy 20:16 00000b Of Wait states Clocks) not support	
(2-2-2) Fast Read Number of Mode Bits 000b: Mode Bits not support 23:21 000b	00H
(2-2-2) Fast Read Opcode 47H 31:24 FFH	FFH
Unused 49H:48H 15:00 0xFFH (0xFFH
(4-4-4) Fast Read Number of 0 0000b: Wait states (Dummy Wait states Clocks) not support 20:16 00000b	00H
(4-4-4) Fast Read Number of Mode Bits 000b: Mode Bits not support 23:21 000b	0011
(4-4-4) Fast Read Opcode 4BH 31:24 FFH	FFH
Sector Type 1 Size Sector/block size=2^N bytes 0x00b: this sector type don't exist 4CH 07:00 0CH	0CH
Sector Type 1 erase Opcode 4DH 15:08 20H	20H
Sector/block size=2^N bytes 0x00b: this sector type don't exist Sector/block size=2^N bytes 4EH 23:16 0FH	0FH
Sector Type 2 erase Opcode 4FH 31:24 52H	52H
Sector Type 3 Size Sector/block size=2^N bytes 0x00b: this sector type don't exist 50H 07:00 10H	10H
Sector Type 3 erase Opcode 51H 15:08 D8H	D8H
Sector Type 4 Size Sector/block size=2^N bytes 0x00b: this sector type don't exist 52H 23:16 00H	00H
Sector Type 4 erase Opcode 53H 31:24 FFH	FFH



Table5. Parameter Table (1): GigaDevice Flash Parameter Tables

Description	Comment	Add(H) (Byte)	DW Add (Bit)	Data	Data
Vcc Supply Maximum Voltage	2000H=2.000V 2700H=2.700V 3600H=3.600V	61H:60 H	15:00	3600H	3600H
Vcc Supply Minimum Voltage	1650H=1.650V 2250H=2.250V 2300H=2.300V 2700H=2.700V	63H:62 H	31:16	2700H	2700H
HW Reset# pin	0=not support 1=support		00	0b	
HW Hold# pin	0=not support 1=support		01	1b	
Deep Power Down Mode	0=not support 1=support		02	1b	
SW Reset	0=not support 1=support		03	1b	
SW Reset Opcode	Should be issue Reset Enable(66H) before Reset cmd.	65H:64 H	11:04	99H	F99EH
Program Suspend/Resume	0=not support 1=support		12	1b	
Erase Suspend/Resume	0=not support 1=support		13	1b	
Unused			14	1b	
Wrap-Around Read mode	0=not support 1=support		15	1b	
Wrap-Around Read mode Opcode		66H	23:16	77H	77H
Wrap-Around Read data length	08H:support 8B wrap-around read 16H:8B&16B 32H:8B&16B&32B 64H:8B&16B&32B&64B	67H	31:24	64H	64H
Individual block lock	0=not support 1=support		00	0b	
Individual block lock bit (Volatile/Nonvolatile)	0=Volatile 1=Nonvolatile		01	0b	
Individual block lock Opcode			09:02	FFH	
Individual block lock Volatile protect bit default protect status	0=protect 1=unprotect	6BH:68	10	0b	EBFCH
Secured OTP	0=not support 1=support	Н	11	1b	
Read Lock	0=not support 1=support		12	0b	
Permanent Lock	0=not support 1=support		13	1b	
Unused			15:14	11b	
Unused			31:16	FFFFH	FFFFH

8. ELECTRICAL CHARACTERISTICS

8.1. POWER-ON TIMING

Figure 39. Power-on Timing Sequence Diagram

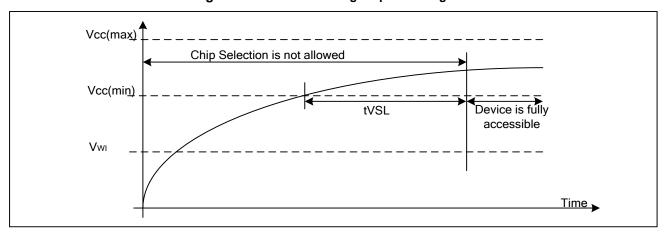


Table6. Power-Up Timing and Write Inhibit Threshold

Symbol	Parameter	Min	Max	Unit
tVSL	VCC (min) To CS# Low	1.8		ms
VWI	Write Inhibit Voltage	1.5	2.5	V

8.2. INITIAL DELIVERY STATE

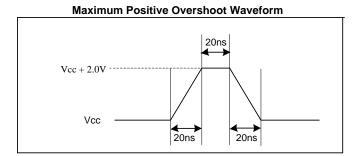
The device is delivered with the memory array erased: all bits are set to 1(each byte contains FFH). The Status Register contains 00H (all Status Register bits are 0).

8.3. ABSOLUTE MAXIMUM RATINGS

Parameter	Value	Unit
Ambient Operating Temperature	-40 to 85	$^{\circ}$
	-40 to 105	
	-40 to 125	
Storage Temperature	-65 to 150	$^{\circ}$
Applied Input/Output Voltage	-0.6 to VCC+0.4	V
Transient Input/Output Voltage (note: overshoot)	-2.0 to VCC+2.0	V
VCC	-0.6 to 4.2	V

Figure 40. Maximum Negative and Positive Overshoot Waveform

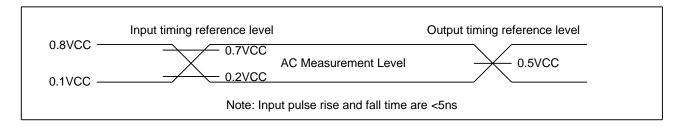
Vss-2.0V

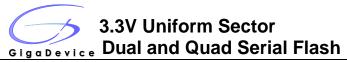


8.4. CAPACITANCE MEASUREMENT CONDITIONS

Symbol	Parameter	Min	Тур	Max	Unit	Conditions
CIN	Input Capacitance			6	pF	VIN=0V
COUT	Output Capacitance			8	pF	VOUT=0V
CL	Load Capacitance		30		pF	
	Input Rise And Fall time			5	ns	
	Input Pulse Voltage	0.1VCC to 0.8VCC		V		
	Input Timing Reference Voltage	0.2VCC to 0.7VCC		V		
	Output Timing Reference Voltage		0.5VCC		V	

Figure 41. Input Test Waveform and Measurement Level





8.5. DC CHARACTERISTICS

(T= -40°C~85°C, VCC=2.7~3.6V)

Symbol	Parameter	Test Condition	Min.	Тур	Max.	Unit.
lμ	Input Leakage Current				±2	μA
ILO	Output Leakage Current				±2	μA
Icc1	Standby Current	CS#=VCC,		1	5	μA
		V _{IN} =VCC or VSS				
Icc2	Deep Power-Down Current	CS#=VCC,		1	5	μA
		V _{IN} =VCC or VSS				
		CLK=0.1VCC /				
		0.9VCC		15	20	mA
		at 120MHz,		15	20	IIIA
laas	Operating Current (Read)	Q=Open(*1,*2,*4 I/O)				
Іссз	Operating Current (Read)	CLK=0.1VCC /				
		0.9VCC		13	18	mA
		at 80MHz,		13	10	mA
		Q=Open(*1,*2,*4 I/O)				
I _{CC4}	Operating Current (PP)	CS#=VCC			20	mA
I _{CC5}	Operating Current (WRSR)	CS#=VCC			20	mA
Icc6	Operating Current (SE)	CS#=VCC			20	mA
Icc7	Operating Current (BE)	CS#=VCC			20	mA
Icc8	Operating Current (CE)	CS#=VCC			20	mA
Icc ₉	High Performance Current			0.6	1.2	mA
VIL	Input Low Voltage				0.2VCC	V
V _{IH}	Input High Voltage		0.7VCC			V
VoL	Output Low Voltage	I _{OL} =100μA			0.2	V
Vон	Output High Voltage	Іон =-100μΑ	VCC-0.2			V

- 1. Typical values given for TA=25°C.
- 2. Value guaranteed by design and/or characterization, not 100% tested in production.

GD25Q40C

(T= -40°C~105°C, VCC=2.7~3.6V)

Symbol	Parameter	Test Condition	Min.	Тур	Max.	Unit.
lы	Input Leakage Current				±2	μA
ILO	Output Leakage Current				±2	μA
Icc ₁	Standby Current	CS#=VCC,		1	25	μΑ
		V _{IN} =VCC or VSS				
I _{CC2}	Deep Power-Down Current	CS#=VCC,		1	25	μΑ
		V _{IN} =VCC or VSS				
		CLK=0.1VCC /				
		0.9VCC		15	20	mA
		at 80MHz,		15	20	IIIA
lass	Operating Current (Read)	Q=Open(*1 I/O)				
I _{CC3}	Operating Current (Neau)	CLK=0.1VCC /				
		0.9VCC		13	18	mA
		at 60MHz,		13	10	IIIA
		Q=Open(*1,*2,*4 I/O)				
Icc4	Operating Current (PP)	CS#=VCC			25	mA
Icc5	Operating Current(WRSR)	CS#=VCC			25	mA
Icc6	Operating Current (SE)	CS#=VCC			25	mA
Icc7	Operating Current (BE)	CS#=VCC			25	mA
Icc8	Operating Current (CE)	CS#=VCC			25	mA
Icc ₉	High Performance Current			0.6	1.5	mA
VIL	Input Low Voltage				0.2VCC	V
VIH	Input High Voltage		0.7VCC			V
Vol	Output Low Voltage	I _{OL} =100uA			0.2	V
Vон	Output High Voltage	Іон =-100μΑ	VCC-0.2			V

- 1. Typical values given for TA=25°C.
- 2. Value guaranteed by design and/or characterization, not 100% tested in production.

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GD25Q40C

(T= -40°C~125°C, VCC=2.7~3.6V)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit.
lц	Input Leakage Current				±2	μΑ
ILO	Output Leakage Current				±2	μA
Icc ₁	Standby Current	CS#=VCC,		1	25	μA
		V _{IN} =VCC or VSS				
I _{CC2}	Deep Power-Down Current	CS#=VCC,		1	25	μA
		V _{IN} =VCC or VSS				
		CLK=0.1VCC /				
		0.9VCC		4.5	20	A
		at 80MHz,		15	20	mA
	Operating Current (Bood)	Q=Open(*1,*2,*4 I/O)				
I _{CC3}	Operating Current (Read)	CLK=0.1VCC /				
		0.9VCC		10	18	mA
		at 60MHz,		13	18	mA
		Q=Open(*1,*2,*4 I/O)				
Icc4	Operating Current (PP)	CS#=VCC			25	mA
Icc5	Operating Current (WRSR)	CS#=VCC			25	mA
Icc ₆	Operating Current (SE)	CS#=VCC			25	mA
Icc7	Operating Current (BE)	CS#=VCC			25	mA
Icc8	Operating Current (CE)	CS#=VCC			25	mA
Icc ₉	High Performance Current			0.6	1.5	mA
VIL	Input Low Voltage				0.2VCC	V
VIH	Input High Voltage		0.7VCC			V
Vol	Output Low Voltage	I _{OL} =100μA			0.2	V
VoH	Output High Voltage	Іон =-100μΑ	VCC-0.2			V

- 1. Typical values given for TA=25°C.
- 2. Value guaranteed by design and/or characterization, not 100% tested in production.

8.6. AC CHARACTERISTICS

 $(T=-40^{\circ}C-85^{\circ}C, VCC=2.7-3.6V, C_L=30pf)$

Symbol	Parameter	Min.	Тур.	Max.	Unit.
	Serial Clock Frequency For: Dual I/O (BBH), Quad I/O				
Fc	(EBH), Quad Output (6BH) (Dual I/O & Quad I/O Without			104	MHz
	High Performance Mode), on 3.0V-3.6V power supply				
	Serial Clock Frequency For: Dual I/O (BBH), Quad I/O				
f _{C1}	(EBH), Quad Output (6BH) (Dual I/O & Quad I/O Without			80	MHz
	High Performance Mode), on 2.7V-3.0V power supply				
	Serial Clock Frequency For: Dual I/O (BBH), Quad I/O				
f _{C2}	(EBH), Quad Output (6BH) (Dual I/O & Quad I/O With High			120	MHz
	Performance Mode), on 2.7V-3.6V power supply				
	Serial Clock Frequency For: Fast Read (0BH), Write Status				
f _{C3}	Register (01H) with or without High Performance Mode on			120	MHz
	2.7V-3.6V power supply				
f _R	Serial Clock Frequency For: Read(03H) Read ID (90H, 9FH			80	MHz
IR.	and ABH), Read Status Register (05H and 35H)			80	IVII IZ
tclh	Serial Clock High Time	4			ns
tcll	Serial Clock Low Time	4			ns
tclch	Serial Clock Rise Time (Slew Rate)	0.1			V/ns
tchcl	Serial Clock Fall Time (Slew Rate)	0.1			V/ns
tslch	CS# Active Setup Time	5			ns
tснsн	CS# Active Hold Time	5			ns
tshch	CS# Not Active Setup Time	5			ns
t _{CHSL}	CS# Not Active Hold Time	5			ns
t _{SHSL}	CS# High Time (Read/Write)	20			ns
t shqz	Output Disable Time			6	ns
t _{CLQX}	Output Hold Time	1.2			ns
t _{DVCH}	Data In Setup Time	2			ns
tchdx	Data In Hold Time	2			ns
t _{HLCH}	HOLD# Low Setup Time (Relative To Clock)	5			ns
tннсн	HOLD# High Setup Time (Relative To Clock)	5			ns
t _{CHHL}	HOLD# High Hold Time (Relative To Clock)	5			ns
tсннн	HOLD# Low Hold Time (Relative To Clock)	5			ns
thLQZ	HOLD# Low To High-Z Output			6	ns
thhqx	HOLD# High To Low-Z Output			6	ns
tclqv	Clock Low To Output Valid			7	ns
twist	Write Protect Setup Time Before CS# Low	20		· ·	ns
tshwl	Write Protect Hold Time After CS# High	100			ns
t _{DP}	CS# High To Deep Power-Down Mode	. 30		20	μs
TOP	CS# High To Standby Mode Without Electronic Signature				μο
t _{RES1}	Read			20	μs
	neau				

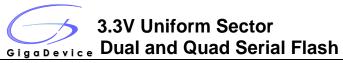


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t _{RES2}	CS# High To Standby Mode With Electronic Signature Read			20	μs
tsus	CS# High To Next Command After Suspend			20	μs
t _{RS}	Latency Between Resume And Next Suspend	100			μs
t _{RST}	CS# High To Next Command After Reset (Except From Erase)			30	μs
t _{RST_E}	CS# High To Next Command After Reset (From Erase)			12	ms
t _W	Write Status Register Cycle Time		5	30	ms
t _{BP1}	Byte Program Time (First Byte)		30	50	us
t _{BP2}	Additional Byte Program Time (After First Byte)		2.5	12	us
t _{PP}	Page Programming Time		0.6	2.4	ms
t _{SE}	Sector Erase Time (4K Bytes)		45	300	ms
t _{BE1}	Block Erase Time (32K Bytes)		0.15	0.7	S
t _{BE2}	Block Erase Time (64K Bytes)		0.25	0.8	S
t _{CE}	Chip Erase Time		2.5	6.5	S

- 1. Typical values given for TA=25°C.
- 2. Value guaranteed by design and/or characterization, not 100% tested in production.



(T= -40°C~105°C, VCC=2.7~3.6V, C_L=30pf)

Symbol	Parameter	Min.	Тур.	Max.	Unit.
	Serial Clock Frequency For: Dual I/O (BBH), Quad I/O (EBH),				
Fc	Quad Output (6BH) (Dual I/O & Quad I/O Without High			70	MHz
	Performance Mode), on 3.0V-3.6V power supply				
	Serial Clock Frequency For: Dual I/O (BBH), Quad I/O (EBH),				
f _{C1}	Quad Output (6BH) (Dual I/O & Quad I/O Without High			60	MHz
	Performance Mode), on 2.7V-3.0V power supply				
	Serial Clock Frequency For: Dual I/O (BBH), Quad I/O (EBH),				
f_{C2}	Quad Output (6BH) (Dual I/O & Quad I/O With High			80	MHz
	Performance Mode), on 2.7V-3.6V power supply				
	Serial Clock Frequency For: Fast Read (0BH), Write Status				
f _{C3}	Register (01H) with or without High Performance Mode on			80	MHz
	2.7V-3.6V power supply				
fo	Serial Clock Frequency For: Read(03H) Read ID (90H, 9FH			60	MHz
f _R	and ABH), Read Status Register (05H and 35H)			60	IVITIZ
t _{CLH}	Serial Clock High Time	4			ns
t _{CLL}	Serial Clock Low Time	4			ns
tclch	Serial Clock Rise Time (Slew Rate)	0.2			V/ns
t _{CHCL}	Serial Clock Fall Time (Slew Rate)	0.2			V/ns
tslch	CS# Active Setup Time	5			ns
tchsh	CS# Active Hold Time	5			ns
tshch	CS# Not Active Setup Time	5			ns
tchsl	CS# Not Active Hold Time	5			ns
t _{SHSL}	CS# High Time (read/write)	20			ns
t _{SHQZ}	Output Disable Time			6	ns
tclqx	Output Hold Time	0.7			ns
t _{DVCH}	Data In Setup Time	2			ns
tchdx	Data In Hold Time	2			ns
thlch	HOLD# Low Setup Time (relative to Clock)	5			ns
t _{HHCH}	HOLD# High Setup Time (relative to Clock)	5			ns
tchhl	HOLD# High Hold Time (relative to Clock)	5			ns
tсннн	HOLD# Low Hold Time (relative to Clock)	5			ns
t _{HLQZ}	HOLD# Low To High-Z Output			7	ns
thhqx	HOLD# High To Low-Z Output			7	ns
t _{CLQV}	Clock Low To Output Valid			7	ns
twhst	Write Protect Setup Time Before CS# Low	20		<u>'</u>	ns
tshwl	Write Protect Hold Time After CS# High	100			ns
t _{DP}	CS# High To Deep Power-Down Mode	100		20	
יטא	CS# High To Standby Mode Without Electronic Signature			20	μs
t _{RES1}	Read			20	μs
tosas				20	
t _{RES2}	CS# High To Standby Mode With Electronic Signature Read				μs
tsus	CS# High To Next Command After Suspend			20	us

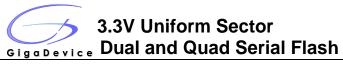


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GD25Q40C

t _{RS}	Latency Between Resume And Next Suspend	100			μs
trst	CS# High To Next Command After Reset (Except From			30	
	Erase)			30	μs
t _{RST_E}	CS# High To Next Command After Reset (From Erase)			12	ms
t _W	Write Status Register Cycle Time		5	30	ms
t _{BP1}	Byte Program Time(First Byte)		30	60	us
t _{BP2}	Additional Byte Program Time (After First Byte)		2.5	15	us
t _{PP}	Page Programming Time		0.6	4	ms
tse	Sector Erase Time(4K Bytes)		45	400	ms
t _{BE1}	Block Erase Time(32K Bytes)		0.15	1.6	S
t _{BE2}	Block Erase Time(64K Bytes)		0.25	3.0	S
t _{CE}	Chip Erase Time(GD25Q40C)		2.5	8.75	S

- 1. Typical values given for TA=25°C.
- 2. Value guaranteed by design and/or characterization, not 100% tested in production.



(T= -40°C~125°C, VCC=2.7~3.6V, C_L=30pf)

Symbol	Parameter	Min.	Тур.	Max.	Unit.
	Serial Clock Frequency For: Dual I/O (BBH), Quad I/O				
Fc	(EBH), Quad Output (6BH) (Dual I/O & Quad I/O Without			60	MHz
	High Performance Mode), on 3.0V-3.6V power supply				
	Serial Clock Frequency For: Dual I/O (BBH), Quad I/O				
f _{C1}	(EBH), Quad Output (6BH) (Dual I/O & Quad I/O Without			60	MHz
	High Performance Mode), on 2.7V-3.0V power supply				
	Serial Clock Frequency For: Dual I/O (BBH), Quad I/O				
f _{C2}	(EBH), Quad Output (6BH) (Dual I/O & Quad I/O With High			80	MHz
	Performance Mode), on 2.7V-3.6V power supply				
	Serial Clock Frequency For: Fast Read (0BH), Write Status				
f _{C3}	Register (01H) with or without High Performance Mode on			80	MHz
	2.7V-3.6V power supply				
f _R	Serial Clock Frequency For: Read(03H) Read ID (90H, 9FH			60	MHz
IR	and ABH), Read Status Register (05H and 35H)			60	IVITIZ
tclh	Serial Clock High Time	4			ns
tcll	Serial Clock Low Time	4			ns
tclch	Serial Clock Rise Time (Slew Rate)	0.2			V/ns
tchcl	Serial Clock Fall Time (Slew Rate)	0.2			V/ns
tslch	CS# Active Setup Time	5			ns
tcнsн	CS# Active Hold Time	5			ns
tsнсн	CS# Not Active Setup Time	5			ns
t _{CHSL}	CS# Not Active Hold Time	5			ns
tshsl	CS# High Time (Read/Write)	20			ns
t shqz	Output Disable Time			6	ns
tclqx	Output Hold Time	0.7			ns
tovch	Data In Setup Time	2			ns
t _{CHDX}	Data In Hold Time	2			ns
t _{HLCH}	HOLD# Low Setup Time (Relative To Clock)	5			ns
thhch	HOLD# High Setup Time (Relative To Clock)	5			ns
tchhl	HOLD# High Hold Time (Relative To Clock)	5			ns
tсннн	HOLD# Low Hold Time (Relative To Clock)	5			ns
tHLQZ	HOLD# Low To High-Z Output	<u> </u>		7	ns
theaz	HOLD# High To Low-Z Output			7	ns
tclqv	Clock Low To Output Valid			7	ns
	Write Protect Setup Time Before CS# Low	20		,	
twist	·				ns
tshwL	Write Protect Hold Time After CS# High	100		200	ns
t _{DP}	CS# High To Deep Power-Down Mode			20	μs
t _{RES1}	CS# High To Standby Mode Without Electronic Signature Read			20	μs
t _{RES2}	CS# High To Standby Mode With Electronic Signature			20	μs



3.3V Uniform Sector Gigabevice Dual and Quad Serial Flash

GD25Q40C

Orguse					
	Read				
tsus	CS# High To Next Command After Suspend			20	μs
t _{RS}	Latency Between Resume And Next Suspend	100			μs
t _{RST}	CS# High To Next Command After Reset (Except From			30	110
	Erase)			30	μs
t _{RST_E}	CS# High To Next Command After Reset (From Erase)			12	ms
t _W	Write Status Register Cycle Time		5	30	ms
t _{BP1}	Byte Program Time (First Byte)		30	60	μs
t _{BP2}	Additional Byte Program Time (After First Byte)		2.5	15	μs
t _{PP}	Page Programming Time		0.6	4	ms
tse	Sector Erase Time (4K Bytes)		45	400	ms
t _{BE1}	Block Erase Time (32K Bytes)		0.15	1.6	S
t _{BE2}	Block Erase Time (64K Bytes)		0.25	3.0	S
tce	Chip Erase Time (GD25Q40C)		2.5	10	s

- 1. Typical values given for TA=25°C.
- 2. Value guaranteed by design and/or characterization, not 100% tested in production.

Figure 42. Serial Input Timing

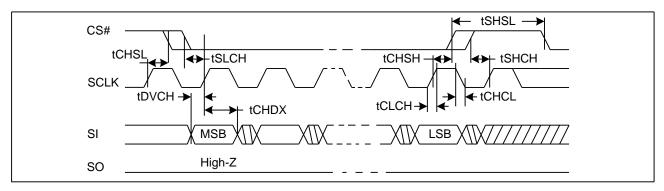


Figure 43. Output Timing

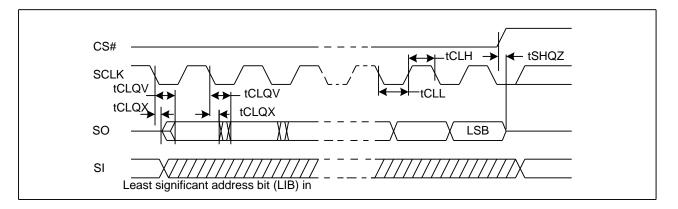


Figure 44. Resume to Suspend Timing Diagram

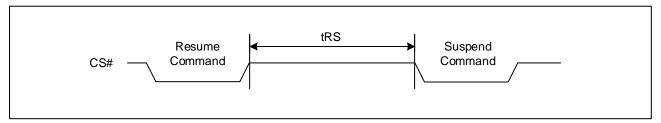
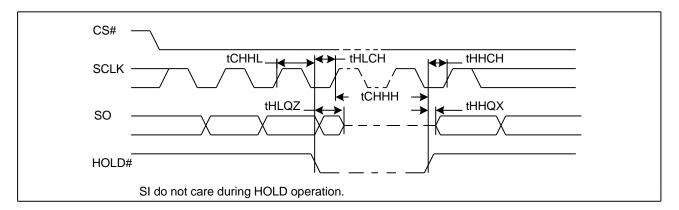
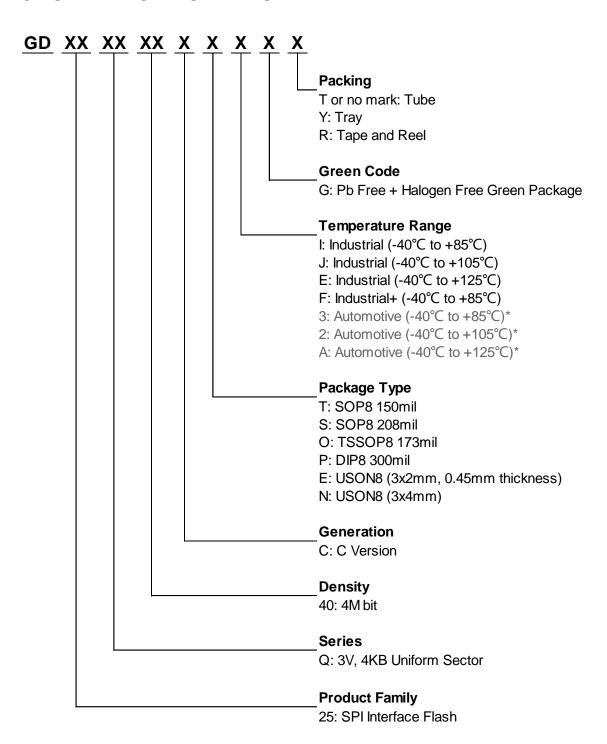


Figure 45. Hold Timing



9. ORDERING INFORMATION



^{*} Please contact GigaDevice sales for automotive products.

9.1. Valid Part Numbers

Please contact GigaDevice regional sales for the latest product selection and available form factors.

Temperature Range I: Industrial (-40°C to +85°C)

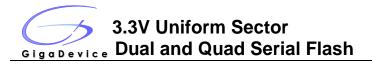
Product Number	Density	Package Type
GD25Q40CTIG	4Mbit	SOP8 150mil
GD25Q40CSIG	4Mbit	SOP8 208mil
GD25Q40COIG	4Mbit	TSSOP8 173mil
GD25Q40CPIG	4Mbit	DIP8 300mil
GD25Q40CEIG	4Mbit	USON8 (3x2mm, 0.45mm thickness)
GD25Q40CNIG	4Mbit	USON8 (3x4mm)

Temperature Range J: Industrial (-40°C to +105°C)

Product Number	Density	Package Type
GD25Q40CTJG	4Mbit	SOP8 150mil
GD25Q40CSJG	4Mbit	SOP8 208mil
GD25Q40COJG	4Mbit	TSSOP8 173mil
GD25Q40CPJG	4Mbit	DIP8 300mil
GD25Q40CEJG	4Mbit	USON8 (3x2mm, 0.45mm thickness)
GD25Q40CNJG	4Mbit	USON8 (3x4mm)

Temperature Range E: Industrial (-40°C to +125°C)

Product Number	Density	Package Type
GD25Q40CTEG	4Mbit	SOP8 150mil
GD25Q40CSEG	4Mbit	SOP8 208mil
GD25Q40COEG	4Mbit	TSSOP8 173mil
GD25Q40CPEG	4Mbit	DIP8 300mil
GD25Q40CEEG	4Mbit	USON8 (3x2mm, 0.45mm thickness)
GD25Q40CNEG	4Mbit	USON8 (3x4mm)

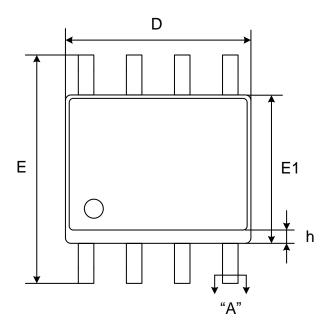


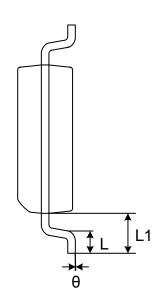
Temperature Range F: Industrial+ (-40°C to +85°C)

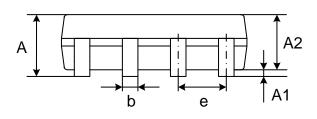
Product Number	Density	Package Type
GD25Q40CTFG	4Mbit	SOP8 150mil
GD25Q40CSFG	4Mbit	SOP8 208mil
GD25Q40COFG	4Mbit	TSSOP8 173mil
GD25Q40CPFG	4Mbit	DIP8 300mil
GD25Q40CEFG	4Mbit	USON8 (3x2mm, 0.45mm thickness)
GD25Q40CNFG	4Mbit	USON8 (3x4mm)

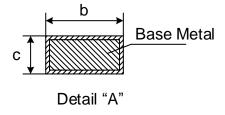
10. PACKAGE INFORMATION

10.1. Package SOP8 150MIL







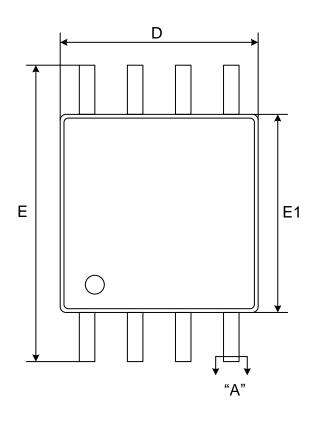


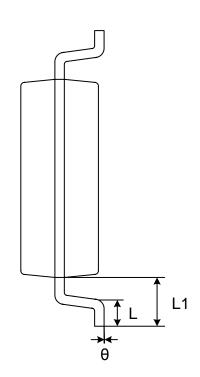
Dimensions

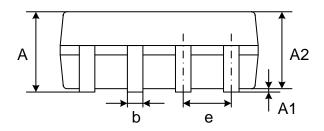
	mbol Jnit	A	A1	A2	b	С	D	E	E1	е	L	L1	h	θ
	Min	-	0.10	1.25	0.31	0.10	4.80	5.80	3.80		0.40		0.25	0°
mm	Nom	-	0.15	1.45	0.41	0.20	4.90	6.00	3.90	1.27	-	1.04	-	-
	Max	1.75	0.25	1.55	0.51	0.25	5.00	6.20	4.00		0.90		0.50	8°

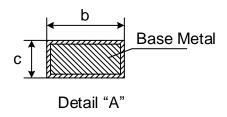
- 1. Both the package length and width include the mold flash.
- 2. Seating plane: Max. 0.1mm.

10.2. Package SOP8 208MIL







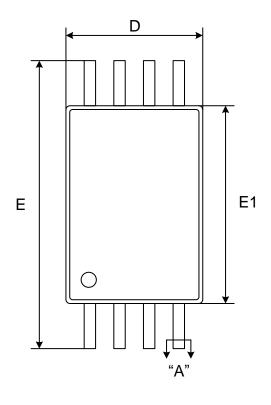


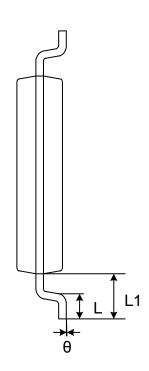
Dimensions

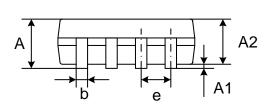
Syı	mbol	Α.	A.1	42	L	_	D	E	E1			L1	0
U	nit	Α	A1	A2	b	С	U	_		е			θ
	Min	-	0.05	1.70	0.31	0.15	5.13	7.70	5.18		0.50		0
mm	Nom	-	0.15	1.80	0.41	0.20	5.23	7.90	5.28	1.27	-	1.31	-
	Max	2.16	0.25	1.90	0.51	0.25	5.33	8.10	5.38		0.85		8

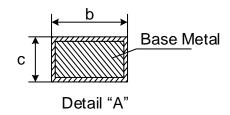
- 1. Both the package length and width do not include the mold flash.
- 2. Seating plane: Max. 0.1mm.

10.3. Package TSSOP8 173MIL







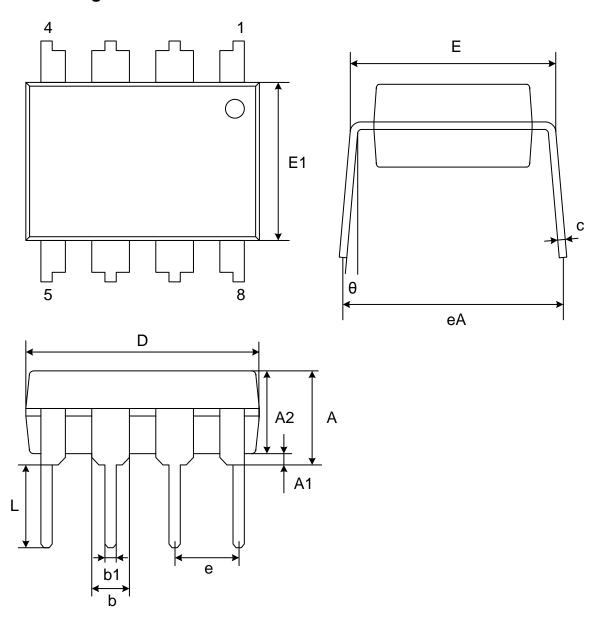


Dimensions

Syı	mbol	۸	۸1	A2	b		D	Е	E1	е		1.1	θ
U	Jnit	Α	A 1	AZ		С		_	E1		_	L1	U
	Min	ı	0.05	0.80	0.19	0.09	2.90	6.20	4.30		0.45		0
mm	Nom	-	0.10	1.00	0.25	0.15	3.00	6.40	4.40	0.65	-	1.00	
	Max	1.20	0.15	1.05	0.30	0.20	3.10	6.60	4.50		0.75		8

- 1. Both package length and width do not include mold flash.
- 2. Seating plane: Max. 0.1mm.

10.4. Package DIP8 300MIL

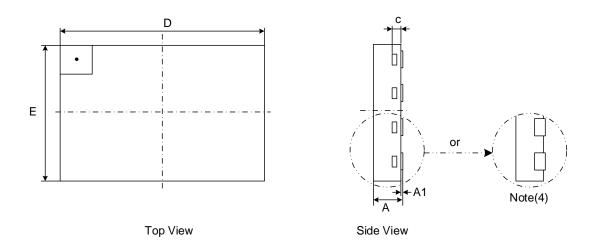


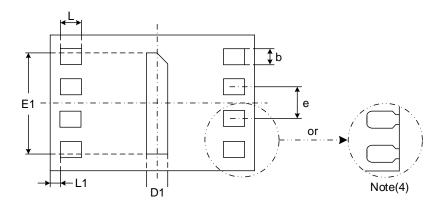
Dimensions

Sy	mbol		A 4	A2	L	h4	С	D	Е	E1			• •	θ
U	Jnit	Α	A1	AZ	b	b1	C		_	E1	е	_	eA	U
	Min	-	0.38	3.00	1.14	0.36	0.20	9.02	7.62	6.10		2.92	8.45	0°
mm	Nom	-	-	3.30	1.52	0.46	0.25	9.27	7.87	6.35	2.54	3.30	8.90	-
-	Max	3.88	-	3.50	1.78	0.56	0.35	9.59	8.26	6.60		3.81	9.35	11°

Note: Both the package length and width do not include the mold flash.

10.5. Package USON8 (3*2mm, thickness 0.45mm)





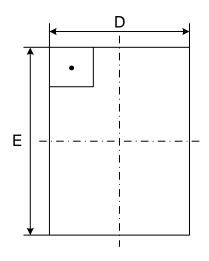
Bottom View

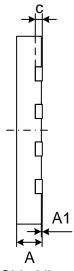
Dimensions

Symbol Unit		Α	A 1	С	b	D	D1	E	E1		L	L1
										е		
mm	Min	0.40	0.00	0.10	0.20	2.90	0.15	1.90	1.55	0.50	0.30	0.10
	Nom	0.45	0.02	0.15	0.25	3.00	0.20	2.00	1.60		0.35	
	Max	0.50	0.05	0.20	0.30	3.10	0.25	2.10	1.65		0.40	

- 1. Both the package length and width do not include the mold flash.
- 2. The exposed metal pad area on the bottom of the package is floating.
- 3. Coplanarity \leq 0.08mm. Package edge tolerance \leq 0.10mm.
- 4. The lead shape may be of little difference according to different package factories. These lead shapes are compatible with each other.

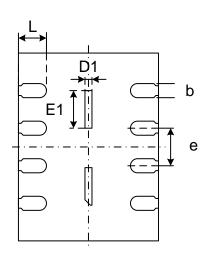
10.6. Package USON8 (3*4mm)





Top View

Side View



Bottom View

Dimensions

Symbol Unit		Α	A1	С	b	D	D1	E	E1	е	L
	Min	0.50	0.00	0.10	0.25	2.90	0.10	3.90	0.70	0.80	0.50
mm	Nom	0.55	0.02	0.15	0.30	3.00	0.20	4.00	0.80		0.60
	Max	0.60	0.05	0.20	0.35	3.10	0.30	4.10	0.90		0.70

- 1. Both the package length and width do not include the mold flash.
- 2. The exposed metal pad area on the bottom of the package is floating.
- 3. Coplanarity ≤0.08mm. Package edge tolerance≤0.10mm.
- 4. The lead shape may be of little difference according to different package factories. These lead shapes are compatible with each other.

11. REVISION HISTORY

Version No	Description	Page	Date		
1.0	Initial Release	All	2016-02-03		
1.1	Modify Chip Erase Time tce	P45	2016-03-07		
1.2	Deleted DATA RETENTION AND ENDURANCE	P41			
	Deleted Output Short Circuit Current	P41	2016-08-11		
	Modify Deep power down current	P43			
	Modify VWI: Min. 2.1V Change to 1.5V	P41			
	Delete Output Short Circuit Current:200mA	P41			
	Modify VCC: -0.6 to VCC+0.4 V Change to -0.6 to 4.0V	P41			
1.3	Add Valid Part Numbers	P48	2016-11-16		
	Modify Package USON8 3*2mm	P52			
	Modify Package USON8 3*4mm	P53			
	Add Package TSSOP8 173mil	P54			
	Modify VCC: -0.6 to VCC+0.4 V Change to -0.6 to 4.2V	P41			
1.4	Update Valid Part Numbers	P48	2017-2-6		
	Update Package SOP8 150mil Dimensions	P49			
4.5	Add Pin Description Note	P5	2017 2 22		
1.5	Modify ORDERING INFORMATION	P47	2017-2-23		
1.6	Modify Write Status Register (WRSR) (01H) Description	P17	2017-3-24		
1.7	Modify the 9 th column in Table1.0	P9	2017-6-2		
1.8	Modify SFDP	P40	2017-6-26		
	Modify Icc9 from 400-800uA to 0.6-1.2mA	P43			
	Delete tRST_P and tRST_R	P45			
1.9	Add tRST, of which the max. value is 30us	P45	2018-3-7		
	Add J and E to 7 th code of ordering information	P47			
	Update the description of all packages	P49-54			
2.0	Add 4BH command	P14			
	Modify tVSL min.value from 5ms to 1.8ms	P41			
	Add tRS to the AC Characteristic, of which the min value is	P47			
	100us		2018-8-16		
	Add DC/AC characteristics @-40 ℃~105 ℃	P44/P48-49			
	Add DC/AC characteristics @-40 ℃~125 ℃	P45/P50-51			
	Modify Ordering Information	P53			
	Remove tSE,tBE1,tBE2 max. values for 50K cycling @-40℃	P48			
2.4	~85℃		2019 40 20		
2.1	Modify tCLQX min. value from 1.2ns to 0.7ns@-40℃~105℃	P49/51	2018-10-29		
	/125℃				

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